A Complete Bibliography of Publications in *Technometrics* for the decade 2000–2009

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17 October 2019
Version 1.02

Title word cross-reference

1 [OH05]. 12 [MS01]. 2^{k-p} [BH00, LM02, MP00]. 2^{m-p} [KT03]. **$69.95** [Zie01-52]. 80^{th} [Gho07]. C_P [Mal00]. D [GV03, Mit00]. $E(s^2)$ [NC08]. F [Ano00e, SBD98]. g [FG06]. h [FG06]. K [SC04, CFP08, LD04]. m [BG06]. μ [BGD05]. n [CFP08]. p [BG06, MW05]. r [BG06]. T^2 [CJFR05].

[**?**]and-Field:2006:MD. **-circulant** [LD04]. **-Control** [BGD05]. **-Means** [SC04]. **-Optimal** [GV03, Mit00, NC08]. [**?**]out-of-Carreras:2008:RSD. **-Run** [MS01].

0-444-50552-0 [Zie05b]. **0-471-23633-0** [Mai05]. **0-471-38491-7** [Zie01-52].

1900 [Zie00o].

2000 [Ano05s, Mye01, Zie02b]. **21st** [Zie01-46, Zie02-45]. **2nd** [Ano09h,

Ano09i, Ano09a, Ano09m, Ano09d, Ano09e, Hey09, Hly09c, Ke09b, Rut09].

3 [Zie00m]. **3rd** [Ano09g, Ano09b, Ano09f, Boo09a, Lip09].

4 [Zie00-44]. **43** [IM02]. **48** [Bri06, Buj06, Efr06, Hub06, Lan06]. **4th** [Bar09, Hor09c].

5 [Das00].

6 [Zie02-30].

95 [Hin06].

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[Ano06p, Ano03g, Ano07o, Ye00]. **Andrea** [Kat04b, Was05, Zie01-36]. **Andreas** [Ano03-46, Ano06-44, Zie01-51, Zie02q]. **Andres** [Che08a]. **Andrew** [Ano05-56, Ano06-27, Ano07x, Baj00, Boo04b, Che01c, Dav03, Gre04, Lew04, Rom06, Ros04, Ye03, Ye05, Zie00d, Zie01-42]. **Andrzej** [Bar08c, Hec09]. **Angel** [Kus02, Kus06]. **Angela** [Ami00]. **Angles** [JP01]. **Anh** [Ano05-53]. **Animal** [Zie00j]. **Anita** [Aba01a]. **Ann** [Ano05-28, Ano06-37, Ano08j, Zel05]. **Annette** [Zie02l]. **Announcement** [Kaf00a, Not03a, Ste09a]. **ANOVA** [Fre03, Gun03, RSB09]. **Answers** [Fam03]. **Anthology** [Ano06-38]. **Anthony** [Ano06-33, Gho07, Kat04b, Por02]. **Antis** [Ano05p]. **Antonio** [Neu08b]. **Antony** [KS07a, Esp06a]. **anyone** [Bri01]. **Aparna** [Bre06]. **AppDev** [Ano08o]. **Application** [Ahm06, BF05, CHCFC04, Che06, FLWZ00, FL07, GB01, Glu06, GV07, Li09, RSB09, Sán06, Zie01l, Kus00]. **Applications** [Ahm08g, Ahm08e, Ano03a, Ano03w, Ano03g, Ano05-58, Ano06-33, Ano07e, Ano08p, Ano08t, Boo05b, CGHL01, Cha01b, DP02, Gho01, Hly07, Jos04, KT05, Liu09b, Lu08, MW04, Mai01, McC06c, MX08, Mic05, Nel00b, Oli02, Oli09d, Ord07a, Ord07b, PM03, PS00, Qia01, Ruk01, San08a, Sen05, Tor01, Was04, Wei03, MW05, MN06, Ano05-55, Ahm07a, Ano06r, Ano07r, Bar07a, Cab04, Cab09, Cha01a, Che02b, Che02a, Den00, Edg04, Gri04, Kar07e, Ker03, Laz05, Lou01, Maz02, McC03b, Mee03, Mye08, Neu08c, Oli08, Pic06, Qia00, Qia02, Sau06, Sha04, Taa02, Zha05, Zie00g, Zie00z, Zie01t, Zie01-34, Zie01e, Zie04q, Zie04x, Zie04h]. **Applied** [Ano03-28, Ano05x, Cab03, Fot09, Glo05, Hem02, Ke09b, Mam09, Oli04, SC00, Zie00-33, Zie00t, Zie01-27, Zie04c, Ano06-42, Ano06-39, Ahm04, Alt02, Alt03, Ami04, Ano04f, Ano05f, Ano05-52, Ano05g, Ano05e, Ano06-39, Ano06h, Ano06-40, Ano09b, Bar09, Boo03, Bri04, Cah06, Con02a, Dob02, Esm09a, Esm09b, Gra00, Hec05, Hey09, Key01, Lew04, Mal05, Mic01, Mor05b, Mye09a, Nem00, Rag01, Ran03, San05, Sar06, Sen06a, Sho03, Sho04, Ye05, Zie00a, Zie00b, Zie01c, Zie02o, Zie02q, Zie02p, Zim01, Zim04, vT00]. **Applying** [Goo02, Nem04, Zie02r]. **Approach** [Ano06-37, AL03a, Che03, Den06, FKQS01, Gun03, GPR05, HPP01, HRV05, JW04a, Jos06a, JS07, LM04, LH02, Lin02, Liu09a, ME04, Miy04, NW04, Pol01, QD04, Sin05, Sud04, SMB01, Weh04, YJL07, ZSC06, ZTL08, vN02, Ahm06, AW05, Ano08m, Cha08b, Che07, Glo05, Gru02, Gun04, HG02, Liu02, Liu06, Oli04, Per04, Qia05, Ruk01, Rut00, Sar05, Sar00b, Sen06b]. **Approaches** [Ano05-56, Mar06, Tom07, ZCC08]. **Appropriate** [Qia05]. **Approximate** [JM00, BG06]. **Approximation** [Ano07t, GS08, HME08, MY08]. **Approximations** [CG09]. **Arabie** [Lip07c]. **Arce** [Liu06]. **Architecture** [Glu06]. **Area** [Ahm07c, Ano04v]. **Areas** [Ano09k]. **Arithmetic** [BG04]. **ARMA** [JTW00]. **Armijo** [Ano08l]. **Armitage** [Ano06m, Zie00l]. **Armstrong** [Ano05s, Mye00]. **Army** [MW05]. **Arnaud** [Sar03]. **Arnholt** [Ng09]. **Arnljot** [Zie04x]. **Arnold** [Boo09b, Rao01, Sea09]. **Arrays** [Den00, KJ09, MMM08, Xu02, ZZJ07]. **Art** [Ano07v, Kal03, Lip09, Maz00]. **Arthur** [Oli09d, Ale02]. **Artificial**

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[Ahm08a, Alt03, Ann06, Ano03-28, Ano03-47, Ano05-52, Ano05-49, Ano05-40, Ano05-56, Ano06-35, Ano06-39, Ano06y, Ano06-41, Ano07w, vB02, Cha05, Che01c, Con05, Fot09, Gre04, Hec09, HL06, Kar07a, LaL09, Law01, Laz03b, Liu04, Mee03, Mye05a, Per04, Pla01, Ray00, Ros04, Rut00, Sea09, Sin08, Soy04, Taa02, Zel05, Zie00u, Zie00m, Zie01-27, Zie01d, Zie01-42, Zie02n, Zie00u]. **Baba** [Ars05]. **Babin** [Qu07b]. **Back** [Ano00a, Ano00b, Ano00c, Ano00d, Ano01a, Ano01b, Ano01c, Ano01d, Ano02a, Ano02b, Ano02c, Ano02d, Ano03b, Ano03c, Ano03d, Ano03e, Ano04a, Ano04b, Ano04c, Ano04d, Ano05a, Ano05b, Ano05c, Ano05d, Ano06a, Ano06b, Ano06c, Ano06d, Ano07a, Ano07b, Ano07c, Ano07d, Ano08a, Ano08b, Ano08c, Ano08d]. **Baclawski** [Pic09]. **Baddeley** [Ano05-49]. **Baecher** [Mye05a]. **Bai** [Bar07a, Zha05]. **Bailer** [Ano06g]. **Baker** [Zie00h]. **Bakir** [Ano08n]. **Balakrishnan** [Ano03p, Ano05u, Ano07e, Ano09d, Boo09b, Che02a, Kar07e, Sea09, Zie00y, Zie00z, Zie01-34]. **Balanced** [HCSC07, KM04, LLI05, Mic05, PKV07]. **Baldi** [Owe04]. **Balding** [Ano03o, Mul08]. **Balgobin** [Zim01]. **Ball** [Zie02x]. **Bands** [JM01, Lom05]. **Bandwidth** [GG04, GLV02]. **Bani** [Zie01s]. **Bank** [LH02]. **Banks** [Zie00m, Zie00v]. **Bärbel** [Ano04i]. **Barbour** [Che08b]. **Barker** [HL06]. **Barnard** [Zie04k]. **Barnett** [Ano05-41, Zie00-44, Ano04s, Zie00f, Zie04h]. **Barrentine** [Rut00]. **Barry** [Boo09b, Jen08, Qu07b, Rao01, Zie01b]. **Bartholomew** [Ano03-45, Lip01]. **Barton** [Bin01]. **Based** [BE03, BGMS03, CG09, DJ07, FG01, Gun04, JLH+06, KM04, KMM08, Mar05, MS00, NM04, NK03, ÖBMT02, Pfa04, QH01, Rob00a, Sar00b, Sen02, SMB01, Whi04, Zha06, ZDCS03, Zie02e, ZTW08, Alt06, Bar08b, Sca07, Sin09]. **Basford** [Hec01]. **Basic** [Ano06-37, Van04, Zie01-50, Zie02-51, Ano05j, Bri05, McC02, Mye00, Zie01d, Zie01e]. **Basics** [Ano03-46, Ano06-44, Boo05a, Zie01-51]. **Basis** [Qia02]. **Basu** [Zie01-41].

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Ahm07c, Ahm08a, Ahm08d, Ahm08b, Ahm08g, Ahm08c, Ahm08f, Ahm08e, Ahm08h, Ahm09, Ale01, Ale02, All01, Alt01, Alt02, Alt03, Alt06, Ami00, Ami04, AC02, AW01, AW05, And08, Ann01, Ann03, Ann06, Ano03i, Ano03m, Ano03r, Ano03-27, Ano03-48, Ano03-36, Ano03-33, Ano03-35, Ano03w, Ano03p, Ano03q, Ano03-40, Ano03-34, Ano03z, Ano03-45, Ano03t, Ano03u, Ano03g, Ano03-49, Ano03x, Ano03v, Ano03s, Ano03-28, Ano03-39, Ano03-41, Ano03-42, Ano03o, Ano03f, Ano03l, Ano03-44, Ano03n, Ano03h, Ano03y, Ano03k, Ano03-29, Ano03-30, Ano03-37, Ano03j, Ano03-46, Ano03-43, Ano03-47, Ano03-38, Ano03-31, Ano03-32, Ano04l, Ano04-30, Ano04-29, Ano04e, Ano04n, Ano04v, Ano04s, Ano04t, Ano04i, Ano04j, Ano04w, Ano04z]. **Book** [Ano04m, Ano04r, Ano04h, Ano04q, Ano04-27, Ano04g, Ano04k, Ano04y, Ano04f, Ano04u, Ano04p, Ano04o, Ano04-28, Ano04x, Ano04-31, Ano05v, Ano05-46, Ano05i, Ano05f, Ano05-32, Ano05-42, Ano05-52, Ano05-27, Ano05-34, Ano05q, Ano05o, Ano05-36, Ano05k, Ano05-43, Ano05t, Ano05-35, Ano05y, Ano05g, Ano05j, Ano05-44, Ano05-47, Ano05r, Ano05s, Ano05m, Ano05x, Ano05-55, Ano05-49, Ano05n, Ano05-30, Ano05z, Ano05p, Ano05-40, Ano05w, Ano05-33, Ano05-39, Ano05-41, Ano05u, Ano05-57, Ano05-45, Ano05-56, Ano05-54, Ano05-53, Ano05-31, Ano05-28, Ano05-37, Ano05-48, Ano05l, Ano05e, Ano05-51, Ano05-38, Ano05-29, Ano05-50, Ano05h, Ano06-33, Ano06w, Ano06t, Ano06-42, Ano06-34, Ano06g, Ano06j, Ano06x, Ano06-43, Ano06r, Ano06p, Ano06z, Ano06i, Ano06e]. **Book** [Ano06-27, Ano06-35, Ano06n, Ano06-31, Ano06q, Ano06-39, Ano06l, Ano06k, Ano06y, Ano06m, Ano06-38, Ano06-41, Ano06u, Ano06-37, Ano06s, Ano06h, Ano06-30, Ano06-28, Ano06-36, Ano06f, Ano06-29, Ano06o, Ano06v, Ano06-32, Ano06-40, Ano07k, Ano07w, Ano07m, Ano07r, Ano07v, Ano07s, Ano07q, Ano07n, Ano07t, Ano07x, Ano07j, Ano07g, Ano07e, Ano07h, Ano07u, Ano07p, Ano07i, Ano07f, Ano07l, Ano07o, Ano08j, Ano08k, Ano08m, Ano08g, Ano08o, Ano08q, Ano08h, Ano08l, Ano08n, Ano08r, Ano08f, Ano08p, Ano08e, Ano08i, Ano09h, Ano09c, Ano09g, Ano09l, Ano09k, Ano09i, Ano09j, Ano09b, Ano09a, Ano09m, Ano09d, Ano09e, Ano09f, Ars05, Avi01, Bab02b, Bab02a, Bab05, Bag05, Bai04, Bai05, Bai07b, Bai07a, Baj00, Bak00, Bak01, Bar02]. **Book** [Bar05, Bar08a, Bar08b, Bar01, Bar04, Bar07c, Bar07b, Bar07a, Bar08c, Bar09, Bas00, Bas02, Bay02, Bel01, Bin01, Bla01, Bod02b, Bod02a, Boo00, Boo03, Boo04a, Boo04b, Boo05a, Boo05b, Boo07a, Boo07b, Boo08, Boo09c, Boo09b, Boo09a, Bor00, Bor02, Bor01, vB02, Bre02, Bre05a, Bre06, Bre05b, Bre01, Bre04, Bre07, Bri03, Bri04, Bri05, Bru00, Buk09, Bur01a, Bur02, Bur00, Bur01b, Bur03, Bur04, Bur06, Bur07, Bur08a, Bur08b, Bur09a, Bur09b, Bzi04, Cab00, Cab03, Cab04, Cab06, Cab08, Cab09, Cah06, Cam01a, Cam01b, Cam02, Car07d, Car07a, Car07b, Car07c, Car00, Cas05, Cha01a, Cha02a, Cha01b, Cha03, Cha01c, Cha02b, Cha04, Cha05, Cha08b, Cha09, Cha00, Che01a, Che03, Che01b, Che01c, Che02b, Che02a, Che07, Che08c, Che08b, Che08a, Chi06, Chi07]. **Book** [Cho06, Cla04a, Cob00, Cob02, Cob04, Con00, Con01, Con02a, Con02b, CL03, Con04, Con05, Cut00, Dan01, Das00, Das04, Das07b, Das07a, Dav03,

Den00, Den04, Den06, Din05, Dob02, Dog01, Dog04, Dok08, Dok09, Dra04, Eas07, Edg04, Esm05, Esm06, Esm09a, Esm09b, Esp06a, Esp06b, Esp07, Eva01, Fah07, Fam03, Fin02, Fin05, Fle09, Fok07, Fot01, Fot04, Fot07a, Fot07b, Fot07c, Fot09, Fre00, Fre03, Fri00, Fri01, Fri05, Gan02, Gan05, Gan06, Gar00, Gat02, Gat06, Geo00, Geo03, Gho01, Gho02, Gho03, Gho05, Gho07, Gho08b, Gho08a, Gho09, Gib01, Glo01, Glo05, Glo06, Gol04, Gol06a, Gol06b, Gol07, Goo02, Gra00, Gra02, Gre04, Gri00, Gri04, Gri07, Gro00, Gru02, Gru05, Gru08, Gun03, Gun04, Gun06, Gup00, Hap00, Hec01]. **Book** [Hec05, Hec07, Hec08, Hec09, Hem02, Hen01, HL06, Hes02, Hes04, Hey01, Hey02, Hey06, Hey09, Hil00, Hin05, Hin06, Hly07, Hly09a, Hly09b, Hly09c, Hof00, HR05, Hol01, Hol08, Hor06, Hor07, Hor09b, Hor09a, Hor09c, Hua00, Hus08, Hut04, HI00, Huz01, HG02, Huz03, Iye02, Jar04, Jar08, Jar09, Jen02, Jen08, Jen09c, Jen09a, Jen09b, Jia03, Joh00, Joh03, Jos04, Kaf03, Kal03, Kal06, Kap03, Kar07b, Kar07d, Kar07c, Kar07e, Kar07f, Kar07a, Kat03b, Kat03a, Kat04a, Kat04b, Kat08a, Kat09, Kat01, Kat08b, Ke05, Ke06, Ke07, Ke08, Ke09a, Ke09b, Ken02, Ken03, Ker02, Ker03, Ket00, Key01, Kia00, Kia01, Kib07, Kim00, Kim04, Kim05, Kok01, KS07b, KS07a, Kuh03, Kuh05b, Kuh05a, Kuo00, Kus00, Kus02, Kus03]. **Book** [Kus06, LaL01, LaL04a, LaL04b, LaL09, Lar08, Law01, Laz03a, Laz03b, Laz05, Lew04, Li06, LH06, LZ02, Lin02, Lip01, Lip05, Lip06a, Lip06b, Lip07c, Lip07b, Lip07a, Lip09, Lit01, Liu02, Liu04, Liu06, Liu07a, Liu07b, Liu09a, Liu09b, Loe07, Lor01, Lor05, Lor06, Lou01, Lu04a, Lu04b, Lu07, Lu08, Lum01, Mag09, Mag00, MM00, Mai05, Mai07, Mai08, Mal05, Mam08, Mam09, Mar03, Mar06, Mat01, Maz02, Maz06b, Maz06a, Maz00, McC00, McC03a, McC07, McC08, McC03b, McC06a, McC02, McC06c, McC03c, McC04, McC05a, McC05b, McG02, McG07, Mee03, MS07, Mic01, Mic03, Mic05, Min02, Mit02, Moo01, Moo03, Mor04, Mor05a, Mor05b, MR00, Mul01, Mul04, Mul08, Mul02, Mur07, Mye00, Mye01, Mye05a, Mye05b, Mye08, Mye09b, Mye09c, Mye09a, Nag04]. **Book** [Nag06, Nas01, Nas02, Nas04, Nas08, Nea07, Nel00a, Nel01, Nem04, Nem08, Nem00, Nem02b, Nem02a, Nem03, Neu01, Neu03, Neu05, Neu08c, Neu08a, Neu08b, Neu09b, Neu09a, Ng05, Ng06, Ng08, Ng09, Nku07, O'N01, O'N03, O'N05, Ode00b, Ode00a, Oli03, Oli04, Oli05, Oli07, Oli08, Oli09a, Oli09c, Oli09b, Olw01a, Olw01b, Ord07a, Ord07b, Owe00, Owe03, Owe04, Owe06, Pan00, Ped01, Per04, Pet03a, Pfa04, Pic06, Pic07, Pic09, Pig06, Pla01, Pla02, Por02, Pry03, Qia00, Qia01, Qia02, Qia05, Qia07, Qiu00, Qiu02, Qiu05, Qiu08, Qu07b, Qu07a, Qu08, Rag01, Ram00a, Ram00b, Ran03, Rao00, Rao01, Rav04, Ray03a, Ray00, Ray03b, Rob00b, Rob02, Rob05, Rob06, Rom03, Rom06, Ros04, Ros05, Ruk01, Ruk02, Rum00, Rum04, Rum06, Rut02, Rut05, Rut09, Rut00]. **Book** [San03b, San03a, San05, San07, San08b, San08a, Sar00a, Sar02, Sar03, Sar05, Sar06, Sar00b, Sau02b, Sau02a, Sau05, Sau06, Sau07, Sca02, Sca04, Sca05, Sca07, Sch04, Sea01, Sea02, Sea05, Sea09, Sen00, Sen05, Sen07, Sen02, Sen06a, Sen06b, Sha02, Sha04, She00, She07, Sho03, Sho04, Sho05, Sin01, Sin06, Sin07, Sin08, Sin09, Slu03, Smi01, Smi02, Smi06, So01, Soy04, Soy09, Spi07, Sta00, Sta04, Ste00b, Ste04, Str01, Sul01, Sym01,

Sym05, Taa02, Tob00, Tob03, Tor01, Umb01, Utl05, Van04, Vol05, Von03, Von06, Vuk00, Wal03, Wal05, Was01, Was02, Was04, Was05, Weh02, Weh04, Wei03, Wik03, Wik05, Wil02, Wil05, Wlu03, Wlu06, Won04, Woo00, Xu06, Yat01, Yat02, Ye00, Ye03, Ye05, Yeh05, Yeh07, Yu07b, Zel00, Zel01, Zel05]. **Book** [Zha05, Zie00u, Zie00-35, Zie00c, Zie00p, Zie00m, Zie00-40, Zie00e, Zie00-45, Zie00n, Zie00i, Zie00o, Zie00d, Zie00-51, Zie00-29, Zie00g, Zie00f, Zie00a, Zie00-48, Zie00-44, Zie00-49, Zie00r, Zie00q, Zie00s, Zie00x, Zie00y, Zie00z, Zie00w, Zie00v, Zie00-36, Zie00-46, Zie00-30, Zie00-47, Zie00-27, Zie00-33, Zie00-41, Zie00-32, Zie00-37, Zie00l, Zie00j, Zie00t, Zie00-39, Zie00h, Zie00k, Zie00-50, Zie00-38, Zie00-42, Zie00-34, Zie00-31, Zie00b, Zie00-28, Zie00-43, Zie01-43, Zie01-28, Zie01j, Zie01-51, Zie01-27, Zie01-38, Zie01-41, Zie01d, Zie01i, Zie01-50, Zie01-36, Zie01s, Zie01x, Zie01-44, Zie01-47, Zie01-49, Zie01-39, Zie01r, Zie01-52, Zie01y, Zie01v, Zie01-33, Zie01-31, Zie01-53, Zie01u, Zie01-42, Zie01-35, Zie01-40, Zie01-29, Zie01a, Zie01m, Zie01-55, Zie01-46, Zie01z, Zie01c, Zie01-30, Zie01o, Zie01t, Zie01n, Zie01k, Zie01q]. **Book** [Zie01g, Zie01l, Zie01h, Zie01p, Zie01w, Zie01-37, Zie01f, Zie01-54, Zie01-34, Zie01e, Zie01b, Zie01-32, Zie01-48, Zie01-45, Zie02-42, Zie02-31, Zie02-36, Zie02-35, Zie02-28, Zie02-48, Zie02-51, Zie02i, Zie02j, Zie02-46, Zie02v, Zie02-45, Zie02-30, Zie02t, Zie02l, Zie02o, Zie02-38, Zie02-41, Zie02-50, Zie02m, Zie02y, Zie02u, Zie02-33, Zie02-34, Zie02q, Zie02-49, Zie02h, Zie02p, Zie02f, Zie02e, Zie02c, Zie02d, Zie02-37, Zie02a, Zie02g, Zie02x, Zie02b, Zie02-27, Zie02-29, Zie02-39, Zie02k, Zie02-47, Zie02-40, Zie02-32, Zie02r, Zie02-44, Zie02-43, Zie02s, Zie02n, Zie02w, Zie02z, Zie03b, Zie03c, Zie03a, Zie04a, Zie04-27, Zie04u, Zie04i, Zie04s, Zie04q, Zie04n, Zie04c, Zie04b, Zie04k, Zie04o, Zie04y, Zie04e, Zie04l, Zie04w, Zie04j, Zie04f, Zie04x, Zie04p, Zie04z, Zie04m, Zie04d, Zie04r, Zie04v, Zie04h, Zie04g, Zie04t]. **Book** [Zie05b, Zie05a, Zie06, Zim00, Zim01, Zim02, Zim04, vN02, vT00]. **Booker** [Ker02]. **Bootstrap** [Ano05-35, CLM04, FG01, JS03, JC06, Weh02, dCGM05, Ano08e, Bab05, Kus00, Was01]. **Borgelt** [Slu03]. **Boris** [Sen00]. **Borror** [Maz06a]. **Bos** [Mam08]. **Bosq** [Ode00b]. **Both** [CR06, GHB+07]. **Boundaries** [Ano07x]. **Bounded** [Oli08]. **Bounds** [Ano09c, FW00]. **Bouvier** [Ano04-27]. **Bowerman** [Zie01i]. **Box** [Ano07p, Pig06, O'N03, Zie01h]. **Boyadjieva** [Rob02]. **Bozdogan** [Ars05, Ano04w]. **Braatz** [Zie02-29]. **Brad** [Zie00-28]. **Bradley** [Ahm09, Sca07, Zie00d, Zie01f]. **Brady** [Hec09]. **Brain** [McC07]. **Branching** [HJM09]. **Brandimarte** [Boo09c]. **Brandt** [Ram00a]. **Brani** [Ket00, Lu08, Sen02]. **Braun** [Hly09a, Gun04]. **Breakdown** [CCD09]. **Breakthrough** [Ale01, Zie04k, Ano05m]. **Breeding** [Hec01]. **Brémaud** [Ode00a]. **Brenda** [Hec09]. **Brereton** [Boo04a]. **Brettner** [Tob03]. **Brewer** [LaL04a]. **Breyfogle** [Zie01x, Ano03q, Gar00]. **Brian** [Ano05j, Ano06e, Ano06-40, Ano09f, Den04, Fri01, Hey01, Ke06, Lip09, Neu09a, Zie01k, Zie02i, Zie02j, Zie02o]. **Briggs** [Bai04]. **Brill** [Hly09b]. **Brillinger** [Ano06-33]. **Britt** [Bar08b]. **Britz** [Law01]. **Bro** [Boo05b]. **Broad** [Ahm06]. **Brocklebank** [Ano04t]. **Brockwell** [Ano03s]. **Brown**

[Zie00a, Ano03-51, Rag01]. **Browne** [Ano05-56]. **Bruce** [Ano04z, Ano04y, Ano06-42, Ano06-31, Din05, Kal06, Rut09, Zie01i, Zie02-44]. **Brunner** [Gho03]. **Bruno** [Nas02]. **Brunsdon** [Zie06]. **Bryan** [Ano05-32, Zie02-43]. **BSE** [Zie01-39]. **Buck** [Ano07x]. **Buehler** [KL02]. **Buncher** [KS07b]. **Buntinas** [Neu05]. **Burdick** [Maz06a]. **Burlew** [Zie00-41]. **Burman** [KB05, MS01]. **Burnham** [Ano03y, MR00]. **Burr** [Maz06b]. **Burrill** [Bre01, Hof00]. **Burt** [Utl05]. **Bury** [Ann01]. **Burzykowski** [Ano06-43]. **Bushman** [Zie00-28]. **Business** [Alt02, Ano03-36, Ano05-36, Ano05-43, Ano05m, Jen08, Kal03, Sar05, She00, Zie04y, Ano06-29, Car07b, Zie01i]. **Butler** [Sta00]. **Buydens** [Zie00u]. **Buyse** [Ano06-43]. **Byron** [Ano03-39, Ano04-31, Dob02].

C [Alt01, Ano03-51, Ano03p, Ano03-34, Ano03x, Ano03o, Ano04t, Ano04j, Ano04h, Ano04k, Ano05-46, Ano05-27, Ano05-47, Ano05s, Ano05p, Ano05-41, Ano05u, Ano06i, Ano06l, Ano06-41, Ano06s, Ano07q, Ano07j, Ano07h, Ano09e, Bar09, Bel01, Boo09b, Bor01, Bri03, Bri04, Bri06, Buj06, Bur01a, Cha05, Che03, Che01b, Das00, Edg04, Efr06, Gho07, Gol06b, Gra02, Gri00, Hes04, Hil00, HR05, Hol01, Hor09b, Hor09a, Hub06, Kap03, Kat04b, KS07b, Kus00, Lan06, Law01, Loe07, Maz06a, Mor05b, Mur07, O'N03, Pla01, Pla02, Qu07b, Ran03, Rao01, Rob06, Rut09, Sea09, Smi01, Soy04, Soy09, Spi07, Vol05, Yat02, Yeh07, Zie00u, Zie00-45, Zie00-48, Zie00x, Zie00y, Zie00z, Zie00w, Zie00-32, Zie00-28, Zie00-43, Zie01-52, Zie01v, Zie01-33, Zie01a, Zie01-46]. **C** [Zie01z, Zie01g, Zie01h, Zie01p, Zie01-32, Zie02-31, Zie02-36, Zie02v, Zie02p, Zie02-27, Zie04d]. **Cache** [GV07]. **Caitlin** [Ano07x]. **Calafiore** [San07]. **Calculated** [Cha02a]. **Calculating** [CCD09, Tom07]. **Calculus** [Ano03g, Ke09b, Zie00o]. **Calibration** [BG05, FJ08, For08, GB01, HSR09, MW04, TG00, Zie04a, Gat02]. **Call** [BJL+07]. **Cambridge** [Ano03-47, Ano07w]. **Campbell** [Zie00m]. **Campolongo** [Che08a, Was05]. **Can** [Gel06]. **Cancer** [Ano07e, Boo07a]. **Cannings** [Ano03o]. **Cannot** [Gel06]. **Cantor** [Liu04]. **Cao** [Lu04b]. **Capability** [Ahm08h, Boy01, Pol01, Vuk00, Yat02, Zim00]. **Caponetto** [Zie02-40]. **Cappé** [Nag06]. **Carbon** [Kva08]. **Care** [Ano05-56]. **Cariboni** [Che08a]. **Carl** [Ahm09, Kar07c, Sca07]. **Carl-Erik** [Kar07c]. **Carleton** [Aba01a]. **Carlin** [Gre04, Zie00d, Zie01f]. **Carlo** [Ahm08d, Ano03-34, Ano05-31, Bor00, Con01, Den06, Hes02, Kim00, McC04, Ode00a, Sar03, BF08, Jon04, LCdC06, MR01, Kuo00]. **Carmen** [Ano05-56]. **Carmichael** [Ano05i]. **Carmona** [Nas02, Zie05a]. **Carol** [Zie02w, Ano09l]. **Carr** [Ano05o]. **Carrera** [Ano06r]. **Carriquiry** [Ye03, Zie00d]. **Carroll** [Kat04a, Wal05]. **Carter** [Tob00]. **Case** [BF05, Mye09c, Ano03-50, vB02, Ye03, Zie00d]. **Casebook** [Sym01]. **Casella** [Zie02-41, Ano05-31, Kim00]. **Cassandras** [Ano09h]. **Castillo** [Rao01, Gho09, Neu03]. **Caswell** [Ano06-42]. **Cate** [Ano03-37]. **Categorical** [Ano08r, Das04, Das07a, GP01, Hap00, JW04a, LM04, ME04, Miy04, NW04, Sud04, Zie01-53, vT00, Ano03i, Zie01j]. **Categorization** [GLM07].

Catherine [Ano09l]. **Causal** [Hea03, Maz00, Ye05]. **Causality** [Zel01]. **Causation** [Bur03]. **Cause** [Bre07, Dan01]. **Cautious** [AK04, BF05]. **Cavanagh** [Zie02-48]. **Cawse** [Zie03a]. **Celebrating** [Gho07]. **Censored** [BSG00, HV07, JM00, JM01, KCM00, LS00, Nel00b, SNS07, Ste04, YW05]. **Censoring** [Kun08, MEM05, NCB04]. **Census** [So01]. **Census-Taking** [So01]. **Centered** [Zie01m]. **Century** [Zie01-46, Zie02-45]. **Cepstral** [Ano00e, SBD98]. **Ceric** [Lew04]. **Cerioli** [Kat04b]. **Cerrito** [Sin08]. **Cesa** [Lip07b]. **Cesa-Bianchi** [Lip07b]. **Cetama** [Bur00]. **Chain** [Ahm08d, Kuo00, Jon04, MR01]. **Chains** [Hly07, Ode00a, Ruk01]. **Chakraborti** [Ano04q]. **Chakravarty** [Sen00]. **Challenges** [GS07, Yu07a]. **Chambers** [Zie04d]. **Champigny** [Ano05s]. **Chan** [CL03, Qia07, Zie01-36, Zie02-50]. **Chance** [Fri05, HI00, Ano07f, Kok01, Neu09a, Zie01k]. **Chances** [Ano05n]. **Chandra** [Mit02]. **Change** [COR08, Wik03, ZH06, ZTL08]. **Change-Point** [COR08, ZH06]. **Changepoint** [GG04, HZ05]. **Changes** [CE02, TH05]. **Chaos** [CL03, Sca05]. **Chap** [Ano03t, vT00]. **Chapman** [Ano03-27]. **Characteristics** [WR02]. **Characterization** [KML04]. **Charles** [Ano05m, Ano06-38, Ano06-41, Gol06b, Ken03, Rag01, Von03, Zie00p, Zie01j]. **Charlton** [Zie06]. **Chart** [CM03, JTW00, LPP00, Rob00a, SJ02, CJFR05, Nel01]. **Charting** [CA06, HMT07, LT09, Umb01]. **Charts** [AL03b, BGD05, CM08, JWT$^+$02, JCR01, LPP00, RS04, RS05, RS06, Umb01, WM05]. **Chatfield** [Ano04-29, Bor02]. **Chatterjee** [Ano07n, Moo01]. **Chattopadhyay** [Sar06]. **Chatwin** [Ano05-41]. **Chau** [Boo05a]. **Checking** [AB04, Bed00]. **Checks** [McC05a]. **Chemical** [Atk05, Boo04a, Boo05b, Nem02b, Zie02h, FVB02, Neu08a]. **Chemistry** [Hor06, Ano03n, Ano05-46, Ano05-40, Zie01l, Zie01-54, Zie04v]. **Chemoinformatics** [Zie04e]. **Chemometrics** [Ano05-33, Zie00u, Zie04v, Boo04a, Boo05a, Zie01l]. **Chen** [Con01, Zha05, Zie02s, Ano03l, Che08b, Glo06, Zim01]. **Cheng** [Gup00, Zie02d]. **Cherkassky** [Ano08k, Lor01]. **Chernick** [Ano03u, Ano08e, Was01]. **Cheryl** [O'N05]. **Chevret** [Nem08]. **Chi** [Gup00]. **Chi-Lun** [Gup00]. **Chiang** [Zie02-29, IM02]. **Chih** [Cab00]. **Chih-Ling** [Cab00]. **Childers** [Esm05]. **Chilès** [Zie00r]. **Chilko** [Bre05b]. **Chin** [Ano09d, Hor07]. **Chin-Diew** [Ano09d, Hor07]. **Cho** [Ano04y, Oli05]. **Choice** [Ano07f, CW02]. **Cholette** [Kar07a]. **Chong** [Fre03]. **Choosing** [LSW09, Qia05]. **Chosen** [HN03]. **Chow** [Ano04-28, Ano05-54, Zie00j, Zie01q]. **Chowdhury** [Bar07c]. **Chris** [Ano04-29, Ano06-41, Bor02, Hap00, Sau02b, Zie06]. **Christensen** [Fam03, Zie02k]. **Christian** [Ano05-31, Ano09k, Kim00, Mye09a, Slu03, Zie04g, Zie04t, Mye05a]. **Christl** [Zie01-39]. **Christophe** [Ano05-53]. **Christopher** [Gan06, Kok01, Nea07, Zie04g]. **Christos** [Ano09h]. **Christy** [Che08c, Chi06]. **Chromatography** [Zie01n]. **Chronologies** [Ano07x].

Chuang [Che08c, Chi06]. **Chuang-Stein** [Che08c, Chi06]. **Chung** [Ano04-28, Ano05-54, Zie00j, Zie01q, Ano07f]. **Cihon** [O'N05]. **Cinar** [Neu08a]. **circulant** [LD04]. **Circulation** [RMGR09]. **Civil** [Baj00]. **Claeskens** [Oli09b]. **Claims** [CLL09, FL07]. **Clark** [Bur03, Mye01, Zie00h, Zie04f, Ami04]. **Clarke** [O'N01, Ano03-41]. **Clarkson** [Ano06-41]. **Class** [ALKP02, Mor00a, SP07, Zie01-55, Zie04z]. **Classical** [Gun00, RG07, Con02b]. **Classics** [Law00, Mor00b, Var00]. **Classification** [Ano05-51, DT02, Epi08, GCS06, JL07, SR04, Soy04, Bar02, Pic07, Zie04a, Sul01]. **Classified** [Ano08r]. **Classifiers** [Bag05]. **Claude** [Bre01, Hof00]. **Clayton** [Ano05r]. **Clemen** [Zie02-32]. **Clifford** [Lou01]. **Clinical** [Ano03-33, Ano03f, Ano03j, Ano04-31, Ano05-56, Ano05-54, Che07, Chi06, Hus08, Sin07, Zie02w, Zie04-27, Zie04l, Zie04-27]. **Clinton** [Sca05]. **Clive** [Ano05-41, Pan00]. **Clock** [JS03, JC06]. **Closed** [VD07, dC02]. **Closed-Loop** [VD07, dC02]. **Cluster** [Ros04]. **Clustering** [Mai01, RG07]. **Cochran** [Ano06-38, Ano05m]. **Code** [MBC00, Kuh05a]. **Coded** [ASW+06]. **Codes** [RBM08, RSB09, RBM11]. **Coding** [Hec07]. **Cody** [Ano06-40, Hol08, San03b]. **coefficient** [Bri01]. **Coefficients** [BK04]. **Cognition** [Fri05, Zie00e]. **Coleman** [Zie03b]. **Coles** [Smi02]. **Collaborators** [Ano09n]. **Collani** [Jen02]. **Collecting** [Iye02]. **Collection** [Zie01d, Zie00h]. **Collett** [Ano04n, Ano04o]. **Collision** [RHOYL06]. **Colored** [HTMW08]. **Colosimo** [Gho09]. **Colton** [Ano06m, Zie00l, Zie02w]. **Column** [HWY02]. **Combinations** [MWJ06]. **Combinatorial** [Den06, Zie03a]. **Combined** [LaL04a]. **Combining** [HG06, SA08, WB05, Bag05]. **Comment** [BH08, Bat08, Cha08a, CW08, Gol08, Han08, HB08, Jon08, KL08, LI08, Old08]. **Comments** [IM02, Mal00]. **Committee** [Zie02h]. **Common** [Ano03j]. **Communication** [Rom06, AC02]. **Companion** [Ano05w, Zie04c]. **Company** [Dok09]. **Comparative** [Rut05, Zie00f]. **Comparing** [Esp06b, FS08]. **Comparison** [BV01, FHR06, Lom05, MBC00, Tom07, Pet03a, McC03a]. **Comparisons** [HWY02, JM00, Mil05, RS06, Zie00-34]. **Compatibility** [JLSZ08]. **Competing** [Con02b, CL05, And08]. **Competing-Risks** [CL05]. **Complete** [Bai05, Ste04, YW05, Zie00-51, Kuh05a]. **Complex** [Ano05-38, Cha09, CG09, Fam03, Oak09, RBM08, ZZ07, RBM11]. **Compliance** [Van02]. **Component** [Ano03-31, Ano06-27, HRV05, Mai07, Ray03b, Jon04]. **Components** [ALKP02, Che02b, Chi01, HN03, Mar05, IM02, MW05, Mic03]. **Composite** [Mee01, MBDD09]. **Compound** [ZZJ07]. **compounds** [FVB02]. **Comprehensive** [Ahm08h, Goo02]. **COMPSTAT** [Zie02b]. **Computation** [GJS09, Ano06i, Con01]. **Computational** [Ano05t, GS07, LH06, Mar06, Nas04, Owe03, Ram00a, Zie02b, Ano06j, Kus02, Ng05, Owe06]. **Computationally** [RSS02, ZSC06]. **Computations** [Ahm08e, MV05]. **Computer** [BBP+07, BBS09, BCL+09, Den04, Dri06, Glo06, Glu06, GV07, HSNB09, HSR09, Hly07, HJM09, LaL04b, LS05, LBH+06, LSW09, McC03b, MBC00, MB06, MMM08, Oak09, QWW08, RBM08, RWH+04, RSB09,

SdHSV03, WCT09, Zie01l, RBM11, Alt06, Bod02a, Zie00g, Zie00h, Zie04f]. **Computer-Aided** [Zie04f]. **Computer-Assisted** [Zie00g]. **Computer-Based** [Alt06]. **Computing** [Ano08h, Bat08, Cha08a, CW08, Gra00, Gui08, Han08, Kus03, LI08, Mai05, Mul04, Old08, Wil08a, Wil08b, Hes02, Lip09, Zie02-40]. **Concentrated** [JP01]. **Concentrations** [Dup05]. **Concepts** [Ano03m, Ano08k, Lor01, Lou01, Zie00p, Kat03a]. **Conceptual** [Dra04]. **Conditional** [Rao01]. **conditioning** [PDDL02]. **Condra** [Zie02f]. **Conduct** [Ano03f, Sin07]. **Confidence** [Ahm04, BG05, Chi01, DM08a, DS00, GD03, HME08, JM00, JM01, KM04, Lom05, Oli09c, IM02, MW05]. **Confusion** [Vuk00]. **Congdon** [Das07a, Gan02, Sho04]. **Congress** [Liu09b, Ord07a, Ord07b]. **Conjecture** [Maz00]. **Connie** [Maz06a]. **Conover** [Gro00]. **Consider** [MS01]. **Constantine** [Ye03, Zie00d]. **Constrained** [GV07, RF05, SdHSV03]. **Constraints** [Smy00, VD07]. **construct** [KB05]. **Constructed** [NC08]. **Constructing** [Chi01, Xu02, IM02]. **Construction** [Ano07x, But04, HWY02, JL07, Mit00, PKV07, Rut05, Xu09]. **Consultant** [Rum00]. **Consulting** [AC02]. **Contamination** [MY08, Zie03b]. **Contemporary** [Car07b, Nem04, So01]. **Content** [FG01]. **Content-Corrected** [FG01]. **Context** [BGMS03, JC06]. **Context-Based** [BGMS03]. **Contingency** [Che03]. **Continual** [Bre01, Hof00]. **Continuous** [Ano05-42, Oli08, Ano09d, Ruk01]. **Continuous-Time** [Ruk01]. **Contour** [RBM08, RBM11]. **Control** [Ahm08h, Ano03-43, AL03b, AK04, Bar08c, BGD05, BGMS03, CM03, CM08, CA06, DW06, DM08b, Edg04, Fre00, Fri00, Gho09, HZ05, HMT07, Hof00, Hor06, Huz01, Jos03, Kaf03, KML04, LWS03, LC00, O'N03, Pla01, RS04, RS06, Rob00a, Ste00a, SJ02, Var00, Wlu06, WM05, ZH06, Zie00-47, Zie00-42, Zie02-30, Zim02, CJFR05, Ano05-27, Ano09a, Bar07b, Hes04, Maz06b, Mit02, Mor04, Neu03, Neu08b, Qiu08, Spi07, Yat02, Zie01v]. **Controlled** [YM00]. **Controller** [FFG06, TTL07, TJ09, dC02]. **Convenience** [GHB+07]. **Cook** [Gra00, Sán06]. **Cookbook** [Zie02c]. **Cooke** [Bas02, Car07d]. **Coordinate** [Che06]. **Copeland** [Esp06b]. **Coping** [Gat02]. **Copulas** [Ray00]. **Corbett** [Zie05b]. **Cornell** [Zie02-28]. **Corporations** [Ale01]. **Corrected** [DS00, FG01]. **Correction** [Ano00e, Ano04-32, Ano05-58, Ano08t, Ano08s, JS03, JC06]. **Correlated** [DWG09, Zho01]. **correlation** [Bri01]. **Correlations** [ŽH09]. **Correspondence** [Hec07]. **Corrosion** [FHR06, RWZF04]. **Counting** [SM04, Liu07a]. **Counts** [So01]. **Couper** [Ano05-29, Ano05-50, Zie00h]. **Course** [Fot09, Hly09a, Kim05, Kok01, Sea09, Utl05, Vol05, Zie01a, LaL01]. **Courtroom** [Zie01-44, Zie02r]. **Covariance** [HMT08, Hub01, JS07, LS00, PP01a, PP01b, RW01, Bur02]. **Covariates** [RLR06, ST06]. **Coverage** [LWY02, RHOYL06, WT09]. **Cowan** [Owe00, Ram00a]. **Cowell** [Ped01]. **Cox** [Ano03-29, Ano07r, Ano07s, Che01a, Gho07, LZ02, Mic03, Ano03-29, Dok08, Zie02t]. **Craig** [Kal06]. **Cramer** [Bar05, JLSZ08]. **Crawley** [Kus03, Ng06]. **Credit** [Kla01]. **Creighton**

[Ano05-28, Ano08j, Ano09g, Zie04n]. **Creveling** [Ano05p]. **Cristianini** [Bre05a]. **Criteria** [BV01, DT02, RACH09, SA08]. **Criterion** [Zho01, KT03]. **Critical** [Ano08s, BN01, Din05, Gui08, VDLB08]. **Cross** [Ano04-31, Ano08r, Boo08, Den06, HTMW08, Ano03k, Ano04-31]. **Cross-Classified** [Ano08r]. **Cross-Cultural** [Ano03k]. **Cross-Entropy** [Boo08, Den06]. **Cross-Over** [Ano04-31, Ano04-31]. **Cross-Section** [HTMW08]. **Crossing** [Ano07x, Hly09b]. **Crossley** [Yat01]. **Crowder** [Ano07l, Con02b]. **Crowe** [Hey02]. **Crowley** [Zie04-27]. **Cultural** [Ano03k]. **Cumulative** [CLM04, GS08, JM01, RS05, Umb01]. **Cupello** [Zie01x]. **Current** [Ano05-41]. **Curvature** [PHSL02]. **Curve** [JQ09, Kuh03, Qia00, Zie02x]. **Curves** [BG05, Qia05, She09]. **Customer** [Bar04, Sin01, Zie01m]. **CUSUM** [LC00, LPP00, QH01]. **Cusums** [UL07]. **Cuthbert** [Zie01r]. **Cycle** [Ng08]. **Cynthia** [Zie00h, Zim00].

D [Aba01b, Aba01a, Ahm08b, AW05, Ano03-35, Ano03-28, Ano03o, Ano03-50, Ano04j, Ano04m, Ano04g, Ano04u, Ano05p, Ano05w, Ano05-54, Ano05l, Ano06-42, Ano06i, Ano06q, Ano06-39, Ano06-29, Ano07m, Ano07r, Ano07s, Ano07l, Ano08p, Bab05, Bak01, Bzi04, Cab00, Cab06, Cab09, Cam02, Car00, Che01a, Che03, Che08b, Che08a, Con00, Dog04, Dok08, Geo03, Gho08b, Gol07, Hol01, Hor09b, Hor09c, Jen09c, Jen09b, Key01, Kia00, Kus00, Laz03b, Mam09, McC03a, Mic03, Mor04, Mor05a, Mul01, Mur07, Mye09c, Ode00b, Olw01b, Rom03, Sch04, Sho05, Soy04, Ste04, Sul01, Tob00, Wei03, Zie00u, Zie00-49, Zie00-34, Zie00-31, Zie00-43, Zie01-27, Zie02-51, Zie02t, Zie03b, Zie04o, Zie04p, Zim01, OH05]. **Dabbene** [San07]. **D'Agostino** [Che08c]. **Dagum** [Kar07a]. **Dahaene** [Car07a]. **Daley** [Sca04]. **Dalgaard** [Ano09i, San03a]. **Dali** [Bar07a]. **Dallas** [Bur02, Nem00]. **Damien** [Bar08c, Ke09b]. **Dan** [Ano06n]. **Dana** [Hey02]. **Dani** [Ahm08d, Kuo00]. **Daniel** [Ami00, Ano05q, Ano05-55, Boo07b, Bre05b, Con05, Mag09, Mye09b, O'N03, Sym01, Zie01-38, Zie01r, Zie01a, Zie01h]. **Dankmar** [Zie00g]. **Darwinian** [ZC06]. **Daryl** [Sca04]. **DasGupta** [Oli09a]. **Data** [Ahm07b, Ahm07c, Alt03, Ano03a, Ano03i, Ano03-40, Ano03-45, Ano04w, Ano04o, Ano05v, Ano05-42, Ano05-52, Ano05-47, Ano05-55, Ano06q, Ano06-39, Ano06-41, Ano06s, Ano06o, Ano06v, Ano06-40, Ano07h, Ano08j, Ano08k, Ano09m, BBJK04, BH08, Bar08b, Boo04a, BCBS08a, BCBS08b, Bri05, Bur02, Cah06, CM08, Cha01c, Cha09, Cha00, Cob04, Coo00b, DLM$^+$07, Epi08, Esm09a, Esm09b, Gat06, Gho01, Gho03, GS07, GP01, Gol07, Gol08, GM01, GHB$^+$07, Gre04, HG06, HPP01, HB08, Hec01, Hec07, HV07, Hol01, HC00, HI00, Huz00, HG02, HN03, Iye02, JM00, JM01, Jen08, JLH$^+$06, JL07, Jon08, Kat04b, KL08, KD05, Kok01, KCM00, Kus03, Kus06, LLBN08, LZ02, Lin02, Lit01, LS00, Lor01, Lu04b, Lu07, MY08, McC06c, Mee03, Mic05, Nel00b, Nem00]. **Data** [Nem03, Neu09b, O'N05, Owe00, Per04, Qu07b, RCGD06, RG07, RA00, Rum06, San03b, San05, Sar06, Sau02b, Sho05, Sin08, Slu03, SNS07, ST06, SB04, SP07, Sym01, Utl05, VD08, Wik05, WW00, Woo00, Ye05, YW05,

Zie00n, Zie00-29, Zie00-46, Zie00-32, Zie01-28, Zie01j, Zie01d, Zie01-52, Zie01y, Zie01f, Zie02o, Zie02n, Zie05a, ZMW08, MN06, Ano03-49, Ano05-53, Ano06-39, Ano03-49, Ano03-41, Ano03h, Ano04n, Ano04g, Ano05-55, Ano06g, Ano07m, Ano08g, Ano08n, Ano08r, Avi01, Boo00, Bre06, Bur06, Car00, Das04, Das07a, Fin02, Fok07, Geo03, Hap00, Hut04, Jar04, Jen09c, Joh03, Kat04a, Ken02, Kia00, Laz03b, Min02, She07, Sin01, Ste04, Wlu06, Zie01r, Zie01-53, Zie04d, Zie04r, Ano03m, Ano03l, Ano05o, Ano05-53, Ano06k, Boo07b, Cab04]. **Data** [Dra04, Gun04, Jen09a, Lou01, Mag09, Mag00, Mar06, Mul04, Nas08, Pic07, Ram00a, Zie00i, Zie01o, Zie01n, Zie02c, Zie04g]. **Data-Analytic** [HPP01]. **Data-Chosen** [HN03]. **Data-Mining** [Ano05-55, KD05]. **Database** [Ano04z]. **Databases** [KFV+07, WM02]. **Datasets** [Cha09, IM05, KS07a, Mai01, MZ02]. **Datta** [Bur09b, Sar06]. **Dave** [Ano07l]. **David** [Ano03-45, Ano03v, Ano03y, Ano04l, Ano04n, Ano04t, Ano04o, Ano05v, Ano05j, Ano05m, Ano05-56, Ano05-48, Ano06-33, Ano06-28, Ano06-32, Ano07r, Ano07s, Ano07q, Ano07h, Ano07i, Ano09j, Bar02, Bod02a, Cha04, Cha09, Con02a, Fah07, Gho07, Gol06b, Gru08, Hin06, Kat01, Lip01, Liu07a, MR00, Mul08, Mye05b, Nas01, Nku07, Ped01, Qu08, Ros04, Sca04, Sch04, Sea05, Sha02, Sho05, Umb01, Wal05, Wil02, Ye03, Zie00m, Zie00-29, Zie00-30, Zie00t, Zie00-38, Zie01-50, Zie01-52, Zie01c, Zie01w, Zie01-45, Zie02-37, Zie03b, Zie04i, Zie04y, Zie05b]. **Davida** [Sta00]. **Davidson** [Cab06]. **Davies** [Zie04a]. **Davis** [Zie01j, Ano03s, Ano05-47, Ken03, LaL09]. **Davison** [Gho07, Kus00, HR05]. **Dawid** [Ped01]. **Dayanand** [Zie00b, Zie01-28]. **Dean** [Ami00, Ano09a, Wlu06]. **Debajyoti** [Zie02s]. **Debnath** [Cha02b]. **Deborah** [Boo04b, Cha01a, Rum04]. **DeCarlo** [Kal06]. **Decelerated** [Sin05]. **Decision** [Ahm08b, Ano05-43, Bla01, Car07b, Mar03, Oak09, She00, Zie02-33, Jen08]. **Decision-Theoretic** [Oak09]. **Decisions** [KLM08, Ano06y, Ano06v, Bur04, Gri07, Zie02-32, Gri07]. **Decomposition** [HC00]. **Decompositions** [Cha09]. **DeCoursey** [Jos04]. **Decreasing** [Pro00]. **Defective** [DM08b]. **Defects** [DM08a]. **Degradation** [BK04, CLM04, SEM09]. **Degree** [GPR05]. **Dekking** [Yeh07]. **Del** [Gho09, Neu03]. **Delaney** [Ano04g]. **Delay** [Ano00e, SBD98]. **Delay-Fired** [Ano00e, SBD98]. **Delfiner** [Zie00r]. **Delivery** [Ano08o]. **Delwiche** [Hor09c]. **Demanding** [RSS02]. **DeMaris** [Ano05-42]. **Deming** [Kaf03]. **Demography** [Ano06-42, Ano06-42]. **Demonstration** [MEM05, MN06]. **Denison** [Soy04, Ros04]. **Dennis** [Gat06, Gra00, Hey01]. **Densities** [FS08]. **Density** [Cab09, GCS06, PC01]. **Denuit** [Car07a]. **Dependence** [Car07d, CS02, Hor07, ŽH09]. **Dependency** [McC06b]. **Dependent** [BGMS03, Car07a, Hut04, RLR06]. **Derek** [Sin01]. **Derivative** [JWT+02, JQ09]. **Derived** [Won04]. **Derong** [Qiu08]. **Derr** [AC02]. **Descriptive** [Bur08a]. **Descriptors** [Epi08]. **Deshpande** [Ahm07b]. **Design** [Alt01, AW01, Ano03f, Ano03-38, Ano05-38, Ano06n, Ano06o, Ano07r, Ano09g, AL03b, Bin01, BC07, BV01, Bzi04, CM08, CL09, Che01a, CE02, CA06, DW06, DT02, Den04, DS06, FLWZ00, FFG06, Glu06, Gol06a, GL09b, HJM09, HWY02, Huz01, Iye02, JW02, Jos03, Jos06a, KJ09, Ke05, KD05,

MB04, MS01, Mor00b, Neu08c, O'N01, O'N03, Oli09d, Pig06, QD04, RBM08, RHOYL06, Rob02, Rut00, Rya08, San07, Sar00b, Sin07, Wei03, ZZJ07, Zie00-35, Zie00p, Zie00n, Zie00-48, Zie00w, Zie00-39, Zie02f, Zie03a, Zie04o, RBM11, Ano04-31, Ano05-54, Zie04-27, Ano08f, Eas07, HL06, Loe07, Nel00a, Qia01, Sta04, Tob00, Xu06, Zie00-32, Zie00-37, Zie00-42, Ami00, AW01, Ano05p, Ano05-54, Ano06l, Ano08f, Ano09e, Din05, Esp06a, Gri00, Hey02, Ke09a, Maz06a, Mor05a, Nem02b]. **Design** [Won04, Xu06, Zie00j, Zie01p, vN02]. **Designated** [KL02]. **Designed** [AW05, GCLH01, Wlu03, YJL07]. **Designing** [For08, Hea03, Ano04g, Lip07a]. **Designs** [AB03, ACBJ09, ALKP02, Ano05-58, Atk05, BFL02, BS03, BV01, BH00, But04, CW02, CLY04, CG09, FM04, GV03, GJS09, Hor09b, KCV02, KT05, LWY02, LN00, LL03, LLY03, LP06, LST07, ML01, Mee01, MS05, Mit00, Mor00a, MBDD09, NC08, PKV07, Rut02, SdHSV03, TG01, VB09, Voe05, WLER06, XCW04, XD05, Xu09, Zho01, KT03, KB05, LM02, LD04, MP00, Ano06h, vB02]. **Desirable** [LST07]. **Desk** [Yat01]. **Destination** [Li05]. **Destructive** [SEM09]. **Desu** [Ste04]. **Detect** [TH05]. **Detecting** [Ano00e, SBD98, WR02]. **Detection** [ASW+06, Bod02a, COR08, Coo00a, Hub01, JLH+06, JQ09, PP01a, PP01b, RW01, WM02, XCW04, ZSC06, Zie02-29, Zie03b]. **Determination** [CHvdW06, HSR09, TTL07, TJ09]. **Determine** [DM08b]. **Determining** [Bla01]. **Deterministic** [HC00, RSB09]. **Deterministic/Stochastic** [HC00]. **Deutsch** [Ano05r]. **Developing** [Hin06]. **Development** [TG00, Zie00j, Zie03a]. **Deviations** [YM00]. **Devices** [LBHB04]. **Devore** [Ano05g, Mic01, Min02, Sau02b, Zie04m]. **Dey** [Ano06i, Zie01s]. **DFSS** [Alt06]. **Dhillon** [Ann06]. **Diagnosability** [Che06, ZDCS03]. **Diagnosing** [AS01]. **Diagnosis** [DM08b, Zie02-29, Bar07b]. **Diagnostic** [Ano03-42, Coo00b, Por02, RA00, McC05a]. **Diagnostics** [BO09, Boo07a, MBG07, SX07, Kuh03]. **Diamond** [Rut02]. **Diane** [Zie04-27]. **Dickey** [Ano04t]. **Dickinson** [Ano04q]. **Dictionary** [Ano03-47, Ano04-30, Ano07w]. **Didier** [Zie00-37]. **Diebold** [Sar00a]. **Dielman** [Alt02, Ano05f]. **Dietrich** [Neu01]. **Diew** [Ano09d, Hor07]. **Differential** [Bur09a]. **Differentiation** [RF05]. **Diggle** [Ano03h, Sin09, Sym05]. **Digital** [FR07]. **Dijksterhuis** [Cha05]. **Dillman** [Zie02-46]. **Dimensional** [Car07d, CG09, Dri06, LHB+02, MZ02]. **Dimensionality** [Lin02]. **Dimitris** [Str01]. **Dineen** [Cab08]. **Dioxide** [dCGM05]. **Dipak** [Zie01s]. **Direct** [Ano07g]. **Directional** [Mai08]. **Dirk** [Boo08, Den06]. **Disciplinary** [Ano07x]. **Discovering** [Ano05-55]. **Discovery** [HI00, HG02, KBS08, LT09, O'N03, Ano04w, Pig06, Zie01h]. **Discrete** [Ano06-34, Ano07m, Ano08g, Ano09h, Che06, FFG06, Kia00, dC02, Ano05q, Fot01]. **Discrete-Part** [Che06]. **Discrete-Time** [FFG06, Fot01]. **Discriminant** [PYC07]. **Discrimination** [HPP01, Zie01-28]. **Discussion** [Bri06, Buj06, Coo00b, DS00, Efr06, Hub06, Hub01, Lan06, RW01, SBF+08, WKT+03, LM04, ME04, Miy04, NW04, Sud04]. **Disease** [Ano03a, Mee03, Ano05-56]. **Dispersion** [BN01, MZ02, ML01]. **Display**

[Mul02, Utl05]. **Distance** [Ano08m, Liu02, Sán06]. **Distances** [Oli02]. **Distributed** [FHR06, KFV+07]. **Distribution** [BSG00, BKG09, Boo09c, CLM04, CS01, FG06, GS08, Jen02, Kar07a, KMM08, Kun08, LPP00, NM04, NCB04, PS00, Weh02, ZS09, Bas00, Bru00, Huz03]. **Distributions** [Ahm07a, Ahm08c, Ann01, JM01, MEM05, Oli08, Sen05, SHY04, Weh02, WW00, Zie04t, Ano05q, Ano06-34, Ano09d]. **Disturbance** [AK04, dC02]. **diverse** [FVB02]. **Division** [Zie02h]. **Dmitrienko** [Che08c, Chi06]. **DNA** [Ano05-54, Ano05-53, Boo07a, Hly09c, Mul08, Das07b]. **Do** [Ano05-53, Gel06, Gol07]. **Dobrivoje** [Ano06j]. **Dobson** [Zie02l]. **Dodge** [Gho07, Ano04-30]. **Dodson** [Hey01]. **Does** [Bri01, Pla01]. **Dolores** [Ng09]. **Domhof** [Gho03]. **dominance** [DGS07]. **Dominici** [Mye09c]. **Dominique** [Cut00, Zie01-35]. **Don** [Ano05i, Zie02-46]. **Donald** [Bar01, Che01c, Esm05, Gre04, Jar04, Law01, Nel01, Pfa04, Rum06, Tob03, Vuk00, Wil05]. **Donev** [Hor09b]. **Donna** [Ano03-42, Ye03]. **Donnelly** [Zie01-39, Bai05]. **D'Orazio** [Kar07f]. **Dorp** [Oli08]. **Dose** [Nem08]. **Dose-Finding** [Nem08]. **Double** [TTL07, TJ09]. **Doucet** [Sar03]. **Douglas** [Ano03-37, Ano04h, Ano05i, Ano05-27, Ano06t, Ano06l, Ano06-41, Ano07j, Bri04, Gra02, Gri00, Kat04a, Maz06a, Ram00b, Spi07, Umb01, Zie00e, Zie01-49, Zie01v, Zie01z, Zie01p, Zie02-31, Zie02-36, Zie02p, Zie02-27, Zie04u]. **Dowdy** [Bre05b]. **Dräger** [Jen02]. **Drähici** [Ano05-53]. **Draper** [Ano07p]. **Driven** [Mag00]. **Drivers** [GM01]. **Dror** [Zie00-34]. **Drug** [Ano04-28]. **Dual** [QD04, CFP08]. **Dual-Response** [QD04]. **Duane** [Bar08a]. **Duckworth** [Zie04y]. **Duda** [Bar02]. **Dudewicz** [Weh02]. **Dugard** [vB02]. **Dummies** [Rum04]. **Dummies(R)** [Kal06]. **Duncan** [Hly09a]. **Dunlop** [Hol01]. **Dunn** [Ami04, Zie02o]. **Dunne** [Liu09a]. **Dunson** [Ano09j]. **Durbin** [Hin05]. **Durrett** [Hly09c]. **Dynamic** [Fot01, Fre00, NK03, RCGD06, RLR06, Sán06, YM00]. **Dynamics** [Lu04b].

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[Law01]. **Gallhofer** [Ke09a]. **Galli** [Ano05s]. **Galwey** [Hec08]. **Gamerman** [Ahm08d, Kuo00]. **Games** [Lip07b]. **Gamma** [ASW+06, BKG09, KMM08, BG06]. **Gamma-Ray** [ASW+06]. **Gao** [Boo05a]. **Garbolino** [Soy09]. **Gardiner** [Sar00b]. **Gareth** [Sar02, Zie00-37]. **Garmt** [Cha05]. **Garrett** [Ano03-49, Ano05e]. **Garthwaite** [Ano03-39]. **Gary** [Sta04, Zie01j]. **Gases** [Nem02a]. **Gasteiger** [Zie04e]. **Gastwirth** [Zie01-44]. **Gatelli** [Che08a]. **Gatsonis** [Ye03, Zie00d]. **Gauge** [Boy01, Maz06a]. **Gaussian** [Bas00, BO09, LS05, Li09, LBH+06, NM04, QWW08, Pic06]. **GCM** [RMGR09]. **Gebhardt** [Esp07]. **Geert** [Ano06-43, Ano07e, Avi01, Chi06]. **Geladi** [Qiu00, Boo05b]. **Gelman** [Boo04b, Gre04, Ye03, Ye05, Zie00d]. **Gen** [Zie02d]. **Gene** [Ano03-49, Ano05-53, Qu08]. **General** [Ahm08g, CHCFC04, Chi01, LLI05, RMGR09, SP07, ZTW07, IM02]. **Generalizations** [Sha04]. **Generalized** [CM08, CS01, DT02, DP02, DS06, Hey09, KM04, MBG07, MW05, MJH00, Mye08, Sen06b, Weh02, WLER06, ZS09, Zie02l, Zie02e, Cha03, Chi07, Gho05, Gho08a, Glo05, Lip05, Qiu05, Von03, Zie01s, Zie02-31]. **Generation** [Ano05-55, Bor00, McC04]. **Genetic** [Ano05-33, Ano05-37, MWJ06, ZC06, Zie02u, Zie02d]. **Genetics** [Zie02u, Ano03o]. **Genichi** [Alt06, Bar07c, Jia03]. **Genome** [Ano07e]. **GENSTAT(R)** [Che01b]. **Gentle** [Neu09b, Ahm08e, Ano05t, Bor00, McC04, Owe03]. **Genton** [Sen05]. **geoENV** [Ano06r, Zie01t]. **Geof** [Owe06]. **Geoff** [Ano06-40, Ano09f, Zie02j]. **Geoffrey** [Ano05-53, Ano07j, Gra02, Mor05a, O'N01, Sha02, Zie01-43, Zie02-31]. **Geographically** [Zie06]. **Geohydrology** [Rag01]. **Geology** [Ano05-47, Ano05h, Was04, Zie00q]. **Geometric** [Rob00a, Lin02]. **Geophysical** [Ano06-33]. **Geophysicists** [Mye05b]. **George** [Ano04l, Ano05k, Ano05-54, Ano05-31, Ano07p, Ano08q, Bri04, Bur02, Cab04, Kim00, Kok01, LaL01, O'N03, Oli03, Pig06, Ruk01, San08b, Sar00b, Zie01a, Zie01h, Zie01w, Zie02-41, Zie02p, Zie02-27, Zie02-47, Zie04y]. **Geosciences** [Ano05o]. **Geoscientists** [Zie05b]. **Geostatistical** [Ano05r, Smi01]. **Geostatistics** [Ano06r, Cha01b, Cob02, Mye01, Zie01t, Ano04p, Mye00, Sin09, Zie00-36, Ano05s, Cob00, Zie00r, Zie00q, Zie00s, Zie01u]. **Geotechnical** [Mye05a]. **Gerald** [Ano05l, Fri00, Neu05, Pry03, Sho03, Ste00b, Zim02]. **Gerhard** [Nas08, Zie02e]. **Gertsbakh** [Tor01]. **Gettinby** [Sar00b]. **Geurts** [Ano07g]. **Ghiocel** [Ano06n]. **Ghosh** [Zie00w, Zie01s, Zie00-35, Zie00c]. **Gibbons** [Ano04q, Zie03b]. **Gibbs** [Ode00a]. **Giesbrecht** [Rut05]. **Gilbert** [Ahm08f]. **Gilchrist** [Glo01]. **Giles** [Zie00t]. **Gill** [Mai05]. **Gillespie** [Hec09]. **Ginevan** [Zie04u]. **Giovanni** [Ano03-49, Zie02-33]. **Giudici** [San05]. **Giulio** [Boo09c]. **Giuseppe** [San07]. **Give** [LC00]. **Given** [GV03]. **Givens** [Owe06]. **Glaz** [Zie01-34, Zie02-39]. **Glen** [Con00, Goo02, Owe00, Ram00a]. **Glenn** [Ano03j, Ano05-43, Bla01, Maz00, She00]. **Glidden** [Gol06b]. **GLIM4**

[Ke06]. **Global** [BGW03, Che08a]. **Glymour** [Bur03]. **Gnedenko** [Sen00]. **Go** [Car07c]. **Goegebeur** [Laz05]. **Goggin** [Zie05b]. **Gokhan** [Ano07v, Ano08n]. **Golberg** [Oli05]. **Goldstein** [Gru08, Ano06w, Zie02-34]. **Golyandina** [Ruk02]. **Gómez** [Zie01t, Ano06r]. **Gómez-Hernández** [Zie01t, Ano06r]. **Gonzalo** [Liu06]. **Good** [Ano03f, Ano05-35, Ano06z, Ano06u, Cha00, Sin07, Zie01-30, Zie02-35, Zie02r]. **Goodness** [BDNN04, CS01, NM04]. **Goodness-of-Fit** [CS01, NM04]. **Goos** [Ke05]. **Goovaerts** [Car07a, Cob00]. **Gordon** [Ano06k, Ano06v, Che07, Zie01y, Zie01o, Ano03-36, Sar03, Sul01]. **Gorman** [Zie01r]. **Goswami** [Fot09]. **Goupy** [Ano09g]. **Govindarajulu** [Gho02, Kat08b]. **Gower** [Cha05]. **Graham** [Zie02o]. **Grahn** [Qiu00]. **Grambsch** [LZ02]. **Grammar** [Bai07b]. **Granfeldt** [Was04]. **Grant** [Zie02g]. **Graphical** [ACBJ09, Esp06b, PYC07, SNS07, Wil02, ZZ07, Bin01, Hec01, Slu03]. **Graphics** [Ano08o, Gun04, Bai07b, Gra00, Gun06, KS07a]. **Graphs** [Sea05, Ahm08b, Mar03]. **Graubard** [Zie01b]. **Gray** [Cab06, Ano05j]. **Green** [Mor05b, Ros05, Zie04-27, Kat04a]. **Gregory** [Cab03, Mye05a, Zie02g]. **Greiner** [Hly07]. **Griffith** [Sym01]. **Grissom** [Ahm06]. **Groundwater** [Gat02]. **Group** [Ano08s, Pet03a, VDLB08]. **Groves** [Ano05-50, Zie02-46]. **Growth** [Kuh03]. **Gu** [Ano06-41, Fre03]. **Guang** [Boo05a]. **Guangbin** [Ng08]. **Gubbins** [Mye05b]. **Guide** [AC02, AW05, Ano03f, Ano08j, Ano08e, Bai05, Cab08, Cha00, Fin05, Hec09, LSW09, McC00, Neu09a, Rum06, Sin07, Zie00-51, Zie04a, Ano06-41, Ano05-43, Che08c, Chi06, Goo02, Hol08, Ker02, LaL09, San03b, She00, Van04, Was01]. **Guided** [KD05, TGLG09]. **Gumpertz** [Rut05]. **Gunst** [Ano03-38]. **Gunter** [Hly07]. **Gupta** [Mor05b]. **Gustafson** [Cla04a]. **Guy** [Ano05i]. **Gygi** [Kal06].

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CCD09, Coo00a, DP02, DS06, Fam03, Gho08a, Glo05, Gol06b, Gra02, Gru08, HBL03, Hey09, LBHB04, MW04, Mal05, MBG07, Moo03, Mye00, Mye08, Peñ05, Qiu04, Rob06, Sen06b, SX07, Von03, WR02, WLER06, Ye00, YW05, ZDCS03, Zie00o, Zie01s, Zie02-31, Zie02l, Zie02e, Zie02k, ZTW07, Avi01, Bor01, Bur01a, Hec09, Mye08, Oli03, Qu07a, Rob05, Rut09]. **Linfield** [Ano03-51]. **Ling** [Cab00]. **Linn** [Fre00]. **Linoff** [Ano06k, Zie01y, Zie01o]. **Liquids** [Nem02a]. **Lisa** [Ano05-54, Cho06]. **Littell** [Moo03, Zie04n, Zie01-33]. **Little** [Hor09c, Laz03b, Ann03, Zie02-46]. **Liu** [Ano05-54, Hes02, Qiu08, Zie00j]. **Livingston** [Ano06-38]. **Lloyd** [Ano05l, Zie02f, Hap00]. **Loader** [Pan00]. **Local** [CHCFC04, DWG09, HBL03, PW01, Qiu04, TGLG09, Pan00]. **Localization** [KLM08]. **Location** [ASW+06, CHvdW06, MZ02, MEM05]. **locations** [BG06]. **Log** [MEM05]. **Log-Location-Scale** [MEM05]. **Logic** [Ano08t, Bar07a]. **Logistic** [Con02a, GLM07, Gol06b, Ano03v, Zie00-31]. **Logistics** [Boo09c]. **Logit** [Bar05]. **Lognormal** [BG04]. **Lohr** [Zie00-39]. **Lomax** [Fin05]. **Lon** [McC07]. **Long** [Whi04]. **Long-Memory** [Whi04]. **Longford** [Ahm07c]. **Longitudinal** [Ano03h, Ano05e, Ano06q, Ano06-39, Avi01, Bur06, Gho03, Lip05, She07, Ano06-39, San03b]. **Longnecker** [Kim05]. **lonosphere** [RMGR09]. **Look** [BGD05]. **Loop** [VD07, dC02]. **Lopes** [Ahm08d]. **Lopuhaa** [Yeh07]. **Lora** [Hor09c]. **Loss** [FFG06, ZCC08, Ano06v]. **Lot** [But04, Van02]. **lots** [LCdC06]. **Louis** [Ano07e, San08a, Zie01f]. **Louise** [Eva01]. **Lovelace** [Zim00]. **Low** [MY08, QW08]. **Low-Accuracy** [QW08]. **Low-Rank** [MY08]. **Lowen** [Sca07]. **Lucy** [Fah07]. **Ludmila** [Bag05]. **Ludwig** [Zie02e]. **Ludwik** [MM00]. **Lugosi** [Lip07b]. **Lui** [Ano05-45]. **Lumelskii** [Sha04]. **Lumley** [Ano05l]. **Lun** [Gup00]. **Lundström** [Kar07c]. **Lunneborg** [Lou01]. **Lunze** [Bar07b]. **Luu** [Zie00-37]. **LuValle** [Din05]. **Lyberg** [Ano03r]. **Lyle** [Zie02u]. **Lyman** [Ano05j, Kar07b, Kim05]. **Lynne** [Law01].

M [Ami04, Ano03-27, Ano03-36, Ano03-33, Ano03o, Ano03-43, Ano03-32, Ano04-27, Ano05i, Ano05-44, Ano05s, Ano05-55, Ano05-30, Ano05p, Ano05-40, Ano05-54, Ano05e, Ano05-29, Ano05-50, Ano06-42, Ano06n, Ano07r, Ano07s, Ano07l, Ano08k, Ano08p, Ano08i, Bab05, Bre04, Cab06, Cam02, Car07a, Cha03, Che01b, Che08a, Esm09a, Esm09b, Fri00, Gan05, Gho09, Gol04, Gru02, Kar07f, Kat03b, Kat04a, Ke08, Ker02, Kib07, LZ02, MM00, Maz06a, McC00, McG07, Mit02, Mur07, Nag04, Nea07, Neu05, Neu09b, O'N01, O'N03, Oli05, Oli09c, Pla01, San08b, Sau05, Sea02, Sen06a, Soy04, Sta00, Ste04, Umb01, Utl05, Wal05, Yeh07, Zie00u, Zie00e, Zie00-45, Zie00-49, Zie00-47, Zie00-41, Zie00h, Zie00-38, Zie01-39, Zie01z, Zie01h, Zie01-48, Zie01-45, Zie02-46, Zie02t, Zie02a, Zie02b, Zie02-40]. **M** [Zie04y, Zie04j, Zie04r, Zie05b, Zim02]. **M.-A** [Ano04-27]. **Mac** [Ano03-51]. **Machine** [Bur09b, Den06, MSM03, Nea07, Neu01]. **Machines** [Pla02]. **MacKay** [McC06a]. **Macro** [Zie00-41]. **Maddala** [Zie00x]. **Made** [Ale02, Zie00-41]. **Magni** [Bay02]. **Mahalanobis** [Jia03, WKT+03].

Maindonald [Gun04]. **Maintenance** [Hey06, MSM03, Ano03-50, Tor01]. **Makes** [Esp07]. **Making** [Ano05-43, She00, Bla01, Car07b, Zie02-33, Jar04, Zie02-32]. **Malinowski** [Ano03n]. **Mallick** [Soy04, Zie01s]. **Mallows** [Bri06, Buj06, Efr06, Hub06, Lan06]. **Malvin** [Sca07]. **Man** [Con01]. **Management** [Ale01, Ano06-36, Hly09b, Smi01, Wei03, Ano06-35, Joh00, Kuh05b, Qia07, Zie02-43]. **Manager** [Ano03f, Sin07]. **Managers** [Zie01-45, Zie04g, Ano05j]. **Managing** [Zie01x]. **Mandallaz** [Mye09b]. **Manly** [Ano05-32, Zie02-43]. **Mannering** [Cob04]. **MANOVA** [Gho05]. **Manufacture** [Ano03-36]. **Manufacturing** [AS01, AL03a, BLC01, Buk09, Che06, McC06a, MNS04, SA08, ZZ07, ZDCS03, dC02, Gol04]. **Many** [LP06]. **Mapping** [Ano05-56, Qu08, Smi01]. **Marc** [Ano06-43, Sen05]. **Marcel** [Bar07b]. **Marchette** [Bod02a, Sea05]. **Marcia** [Rut05]. **Marco** [Kat04b, Por02, Was05]. **Marcoulides** [LaL01]. **Marcus** [Zie01d]. **Mardia** [Mai08]. **Margaret** [Ano05-51, Mye00, Zie01u]. **Margins** [Bar08a]. **Margo** [So01]. **Mari** [Ano04r]. **Maria** [Boo09b, Ng09, Rao01]. **Marian** [Zie01-36]. **Marianna** [Sha04]. **Mario** [Bai04, McC06c, Mic05]. **Marjorie** [Ano03-43, Zie00-47]. **Mark** [Ano06o, Olw01a, Sen06b, Yat01, Zie00n, Zie01-49, Zie01-45]. **Marketing** [Ano05-58, KT05, Oli09d, Ano04z, Kib07]. **Markets** [Ano03-27]. **Markos** [Che02a]. **Markov** [Hly07, Mag09, Nag06, Pic06, Ruk01, BLC01, Jon04, LHB+02, MR01, Ahm08d, Kuo00, Ode00a]. **Markovian** [Pic05]. **Marlene** [Lor05]. **Marshall** [Ahm08c]. **Martens** [Bay02, Bay02]. **Martijn** [Ano06h]. **Martin** [Ano05-29, Ano07l, Con02b, KS07a, Lip01, Neu05, Zie00h, Zie02-45, Zie06, Ano06t]. **Martinez** [Huz03, Kus02, Kus06, Kus02, Kus06]. **Martingale** [BE03]. **Martingales** [Yu07b]. **Martz** [Hor09a]. **Marvin** [Cab09, Zie04x]. **Mary** [Ker02]. **Mask** [ASW+06]. **Masking** [CL05]. **Mason** [Ano03-38, Edg04]. **Massart** [Zie00u]. **Massive** [JL07, Mai01]. **Mastering** [Zie01y]. **Matching** [Kar07f, Ano04x]. **Materials** [Qiu02, Ste09b, Zie03a]. **Mateu** [Zie04q]. **Math** [Ano07k]. **Mathematical** [Ano06-42, Ano08l, Boo09b, Cab08, Cha01a, Geo00]. **Mathematics** [Mam09, Zie02-51, Boo09a, Nku07]. **Mathew** [Ye00]. **Mathieu** [Zie00-37]. **Matignon** [Jen09a]. **MATLAB** [Lip07c]. **MATLAB(R)** [Kus02, Kus06]. **Matrices** [DT02, Li05, Lip07c, MY08]. **Matrix** [Bur01b, Cha09, HMT08, Hub01, PP01a, PP01b, RW01, Ahm08e, Kar07d]. **Matroid** [Che06]. **Matter** [Ano00a, Ano00b, Ano00c, Ano00d, Ano00f, Ano00g, Ano00h, Ano00i, Ano01a, Ano01b, Ano01c, Ano01d, Ano01e, Ano01f, Ano01g, Ano01h, Ano02a, Ano02b, Ano02c, Ano02d, Ano02e, Ano02f, Ano02g, Ano02h, Ano03b, Ano03c, Ano03d, Ano03e, Ano03-52, Ano03-53, Ano03-54, Ano03-55, Ano04a, Ano04b, Ano04c, Ano04d, Ano04-33, Ano04-34, Ano04-35, Ano04-36, Ano05a, Ano05b, Ano05c, Ano05d, Ano05-59, Ano05-60, Ano05-61, Ano05-62, Ano06a, Ano06b, Ano06c, Ano06d, Ano06-45, Ano06-46, Ano06-47, Ano06-48, Ano07a, Ano07b, Ano07c, Ano07d, Ano07y, Ano07z, Ano07-27, Ano07-28,

Ano08a, Ano08b, Ano08c, Ano08d, Ano08u, Ano08v, Ano08w, Ano08x]. **Matters** [Dra04]. **Matthew** [Cob04]. **Matthias** [Zie01l]. **Maura** [Zie01j]. **Maurer** [Wei03]. **Maximin** [SdHSV03]. **Maximization** [JW04a, LM04, ME04, Miy04, NW04, Sud04]. **Maximize** [AB03]. **Maximum** [YW05]. **Maxwell** [Ano04g, Dra04]. **May** [Zie04f]. **Maynard** [Ano03-37]. **McBean** [Zie00-46]. **McBride** [Ano06-35]. **McCabe** [Zie04y, Ano04l, Zie01w]. **McClish** [Ano03-42]. **McConnell** [Kuh05a]. **McConway** [Che01b]. **McCuen** [Ano03-32, Ke08, Wik03]. **McCulloch** [Von03, Gol06b, Kib07]. **McDonald** [Mai05, Mam09]. **McKnight** [Neu09b]. **McLachlan** [Ano05-53, Sha02]. **McLean** [Dog01]. **McNulty** [Ano08l]. **McPherson** [Goo02]. **McQuarrie** [Cab00]. **McShane** [Ano05-54]. **Meadows** [Zie01x]. **Mean** [BG04, CE02, HZ05, ÖBMT02, RS06, TH05, UL07, Van02]. **Means** [Esp06b, MWJ06, ND02, SC04, Pfa04]. **Measure** [JW04b, Cla04b]. **Measurement** [BMS09, Bur00, Cha01c, CR06, Gup00, Ste00a, VD08, Zie02h, Zie04u, Ars05, Cla04a]. **Measurements** [Kva08, LWS03, Bar08a, Ken03, Kia01]. **Measures** [Car07a, GP06, Gho05, Gol06b, Ahm08h, Nag04, Yu07b]. **Measuring** [LBHB04, Aba01a]. **Mechanical** [Qia01, Ann03, Tob00]. **mechanics** [MR01]. **Mechanisms** [Lip07a]. **Media** [LHB+02]. **Medical** [Ano04o, Ano05-51, Ano06-40, Gol07, Liu04, Zie02-33, Zie02n]. **Medicine** [Ano03-42, Zie00a]. **Meeker** [DS00]. **Meer** [Hly07]. **Meester** [Yeh07]. **Megavariate** [Nem03]. **Mehmed** [Ano03m, Ano05-55]. **Meier** [Ano05-46]. **Melania** [And08]. **Melvin** [Ano03-46, Ano06-44, Zie01-51]. **Memorabilia** [Ano07f]. **memoriam** [Kaf01b]. **Memory** [Whi04]. **Mendenhall** [Kar07b]. **Meng** [Ye05]. **Mesbah** [Ano07e]. **Messy** [Bur02]. **Métais** [Ano07g]. **Metcalfe** [Baj00]. **Method** [AS01, CHCFC04, Chi01, Den06, Esp06b, For08, HG06, HWY02, JTW00, JW04a, LM04, ME04, Miy04, NW04, Sud04, ZS09, ŽH09, IM02, LCdC06, Boo08, Che08b, Zie01-35]. **Methodologies** [Che02b, Maz02, Sar06]. **Methodology** [Ano07o, Kaf01c, Ano05-50, McG02, Rao00, Zie02-36]. **Methods** [Aba01b, Ahm04, Ano03m, Ano03-40, Ano03-41, Ano03-42, Ano03j, Ano04r, Ano04y, Ano05-46, Ano05-33, Ano05-41, Ano05-57, Ano05-38, Ano06-43, Ano06-35, Ano06q, Ano06u, Ano07r, Ano07t, Ano07e, Ano08m, Ano08l, Ano08e, Ano09l, BBJK04, Bag05, Bin01, Boo07b, Bre05a, BN01, Bur01b, Cha00, Che01c, COR08, Cob04, Con01, Gan06, Gho05, Glo06, Gol04, Gol06b, Hly09b, Hut04, HN03, Joh03, Kar07a, Kat09, Ken03, KD05, KCV02, KMM08, Kuh05b, Kus00, LaL01, Lit01, Liu02, McC03a, McC02, McC06c, MBC00, Mic05, Mye09c, Nem08, Nem00, Ng05, Oli07, PHSL02, Qia00, Ram00a, Rom06, San07, Sar03, Slu03, Smy00, Soy04, Ste04, Was01, Was02, Won04, ZM06, Zie00-45, Zie00-33, Zie01-41, Zie01-42, Zie01-40, Zie01f, Zie02v, Zie02g, Zie03b, Zie04x, Zie04h, ZTW08, Ahm07b]. **Methods** [Ano03k, Ano04s, Ano05-32, Ano05-31, Ano06z, Ano08k, Bab02b, Bar09, Bas02, Bor00, Gar00, Gho02, Gru08, Hey06, Hin05, Key01, Kim00, Kim05,

Lar08, Lor01, Lu04a, Mag00, McC04, Nas04, Ram00b, Ran03, Sca04, Sea01, Weh02, Wik03, Wil05, Yat01, Zie00y, Zie02-35, Zie02a, Zie02z, Zie04s, Ano03w, Ano03x, Ano05-29, Ano07l, Kat03b]. **Metrics** [Mai01]. **Meulman** [Lip07c]. **Meyer** [Ker02]. **Mi** [Esm06]. **Micah** [Mai05]. **Michael** [Alt01, Ano03u, Ano03-29, Ano04-31, Ano05v, Ano05-36, Ano05w, Ano05-54, Ano06k, Ano06-36, Ano08e, Bar07b, Bar08c, Bre02, Din05, Gru08, Hor09a, Ke07, Kim05, Kus03, Lin02, Mai05, Ng06, Qia05, Sar05, Str01, Was01, Woo00, Zie00-29, Zie00q, Zie01i, Zie01y, Zie01-53, Zie01o, Zie01-37, Zie02-44, Zie04u]. **Michalidis** [Bur09b]. **Michele** [Zie00-41, Bur00]. **Michiko** [Sin06]. **Mick** [Ano05-29, Ano05-50, Zie00h]. **Mickey** [Ami04]. **Microarray** [Ano03-49, Ano05-54, Ano05-53, BH08, BCBS08a, BCBS08b, Gol08, HB08, Jon08, KL08]. **Microarrays** [Ano05-53, Boo07a]. **Microsimulator** [MBB05]. **Microsoft** [Sho03]. **Microsoft(R)** [Jos04, Zie00-38, Zie01-45, Zie04g]. **Microstructures** [Qiu02]. **Mielke** [Ano08m, Liu02]. **Miguel** [McC06c, Mic05]. **Mike** [Zie00d]. **Mikel** [Ale01]. **Mikhail** [Ano09l]. **Militino** [Ng09]. **Millard** [Lum01, Zie02q, Ano07x]. **Miller** [Esm05, Zie04v, Ano03-44, Cab03, Zie04v]. **Milliken** [Bur02]. **Million** [KS07a]. **Min** [Hor07]. **Mind** [Ano05-30, Sea02]. **Minefields** [WR02]. **Miner** [Sin08]. **Mineral** [Ano06p]. **Miner**^{TM} [Jen08, Jen09a]. **Mines** [WR02]. **Ming** [Con01, Gri04, Zie02s]. **Ming-Hui** [Con01, Zie02s]. **Minghui** [Zim01]. **Minimal** [RHOYL06]. **Minimizers** [PW01]. **Minimum** [DT02, RWZF04, Sco01, KT03]. **Mining** [Ano03m, Ano03l, Ano04w, Ano05-55, Ano06k, Ano06s, Ano09m, Boo07b, Cab04, Cha09, Jen08, Jen09a, JL07, KD05, Mag09, Mul04, Sin08, Zie01o, Zie02c, San05, Slu03, Zie00i, Zie01y]. **MINITAB** [Bai07a, HI00]. **Minquez** [Boo09b]. **Misclassification** [Cla04a, JL07]. **Mises** [JLSZ08]. **Missing** [Fok07, Laz03b, Ahm07c, Neu09b]. **Mission** [Din05]. **Mission-Critical** [Din05]. **Misspecification** [ACBJ09, Pas06]. **Misused** [Eva01]. **Mitchel** [Ano03v, Ano06-32]. **Mitchell** [Zie02z]. **Mitra** [Bur09b, Mul04]. **Mitsuo** [Zie02d]. **Mixed** [Avi01, Che02b, Gho05, Hec08, Hec09, Khu06, LLI05, Mye08, Qu07a, Von03, Xu02, Ye00, ZDCS03, Zie00a, Zie01z]. **Mixed-Effects** [ZDCS03, Zie01z]. **Mixture** [DP02, KCV02, PHSL02, PDDL02, Sha02]. **Mixtures** [Ano07p, SS01, Zie00g, Zie02-28]. **MLwiN** [Ano05-56]. **MODA** [Zie00-32]. **Modarres** [Olw01a]. **Model** [ACBJ09, Ano09j, AL03b, AK04, AB04, Atk05, BK04, BFL02, BC07, Cab00, CS02, CL05, FJ08, LN00, Oli09b, PM03, Pas03, Qu07a, RdC05, RMGR09, Sha04, SHY04, ST02, WLER06, ZH06, Zie00-32, Jon04, PDDL02, LZ02, Ano03y, MR00, Oli09b, Sin09]. **Model-Based** [Sin09]. **Model-Checking** [AB04]. **Model-Oriented** [Zie00-32]. **Model-Robust** [LN00, PM03, RdC05]. **Modeling** [Ano04z, Ano05-42, Ano06i, BBS09, Bla01, Boo09b, Buk09, Cha08b, Cob02, FM04, FR07, Gel06, GLV02, GM01, Gri04, Hly07, Huz00, IM05, Ket00, LH02, Lip05, Mor00a, Olw01b, QW08, Qiu08, RWZF04, San08b, Sau02a, Sco01, Sen07, Sen06a, She09, Smi02, Wal03, Wik05, WLLZ07, Ye05, Ano05r, Ano06-31, Bur01b, Fin05, Lew04, Zie02k, Ano03z, Bur06, Bur07, Fot07b, Huz01, LZ02, Owe04, Wik03, Zie02-33]. **Modelling** [Ano04j, Che01b, Gat02,

Glo01, Hec08, Ke06, Oli04, Zie02-34, Zie02e, Car07d, Dob02, Gan02, Hil00, Rob00b, Ros04, Sho04, Wil02, Ano04n, Ano04o, Bur00, Lu04b]. **Models** [Ahm07b, Ahm08g, Ano03m, Ano05-52, Ano06y, Ano06-28, Ano06v, Ano07l, Ano09l, Ano09k, AB04, Avi01, Bar05, BE03, BBP+07, BCL+09, Bed00, BV01, Bor01, Bre06, Bur01a, CHCFC04, Che02b, Chi07, CCD09, Con05, CG09, DWG09, Das07b, Das07a, DS06, Esm06, GP06, Gho08a, GB01, Glo05, Glu06, GV07, Hec09, Hey06, Hly09b, Hly09c, Hua00, Huz00, Joh03, Kat03a, Ke07, Ker03, Khu06, KM04, Kuh03, LHB+02, LS05, LLI05, LBHB04, LBH+06, Lip01, MBG07, McC03a, McC02, McC06c, Mic05, MMM08, Mye08, Oak09, OH05, QWW08, RCGD06, Ray03a, RLR06, RSB09, RSS02, RF05, Rob05, Rob06, Rut09, Sán06, Sen06b, SX07, Slu03, ST06, SB04, SP07, SMB01, TG00, WCT09, WLER06, YS05, Zel01, ZZ07, ZDCS03, Zie00a, Zie00-43, Zie01z, Zie04x, Ano03w]. **Models** [Ano06w, Ano06-27, Boo07b, Car07a, Dog04, Fam03, Fot01, Fre03, Gho05, Gol06b, Hey09, HR05, Lip05, Lor05, McC03c, Moo03, Nag06, Qu07a, Rao01, Sen02, Sha02, Sho05, Sin06, Vol05, Von03, Ye00, Zie01s, Zie02-31, Zie02l, Zie02e, Ano03-27, Ano07m, Kia00, Kia01, She07]. **Modern** [Ahm07c, Ano06t, Bab02b, Fot04, Loe07, Rya08, Yeh07, Ano03-28, Ano08l, Bod02b, Eas07, Zie00-33, Zie01-27]. **modification** [FVB02]. **Modified** [MWJ06, YW05]. **Modular** [AW05]. **Modulating** [ASW+06]. **Moeschberger** [Rav04]. **Mogens** [Bar07b]. **Mohamed** [Nag04]. **Mohammad** [Olw01a]. **Mohammed** [Mat01]. **Mohler** [Ano03k]. **Molecular** [Ano06-43]. **Molecule** [LWY02]. **Molenberghs** [Ano06-43, Chi06, Ano07e, Avi01]. **Møller** [Nas04]. **Moment** [NM04, XD05]. **Moment-Based** [NM04]. **Monahan** [Was02]. **Money** [Esp07]. **Monitoring** [BGMS03, Che07, Gho09, GP01, Hus08, JTW00, JWT+02, LT09, NK03, RS06, Zie00-46, Zie01-43, ZTW07, ZTW08, Bod02a]. **Monroe** [Zie00e]. **Monte** [Ahm08d, Ano03-34, Bor00, Den06, Kuo00, McC04, Ode00a, Sar03, BF08, Jon04, LCdC06, MR01, Ano05-31, Con01, Hes02, Kim00]. **Monte-Carlo** [Den06]. **Montes** [Zie04q]. **Montgomery** [Ano07j, Bri04, Gra02, Zie02-31, Zie02p, Zie02-27, Ano04h, Ano05-27, Ano06l, Gri00, Maz06a, Spi07, Zie01v, Zie01p, Zie02-36]. **Moore** [Ano04l, Zie01w, Zie04y, Zie01-50]. **Morgan** [Zie00-28, Dob02]. **Morris** [Ahm09]. **Morrison** [Wil05]. **Morton** [Zie01-32]. **Moses** [Ano05z]. **Moshe** [Ano08q]. **Mosteller** [Ano07h, Zie01-52, Ano07q]. **Motion** [FR07]. **Moulines** [Nag06]. **Mounir** [Ano07e]. **Moustaki** [Ano03-45]. **Moving** [AL03b, CM03, CE02, HMT07, HMT08, JCR01, RS05, RS06, Rob00a, TTL07, TJ09, ZTW07]. **Moyé** [Hus08, Zie04l]. **MR2248365** [Bri06, Buj06, Efr06, Hub06, Lan06]. **MR2414514** [TJ09]. **MR2655651** [RBM11]. **Mücklich** [Qiu02]. **Mukerjee** [Loe07]. **Mukhopadhyay** [Sar06, Kat08a]. **Mulier** [Ano08k, Lor01]. **Muller** [Gun03, Key01, Qu07a, Sen02, Lor05, McC03a, Iye02]. **Mullins** [Hor06]. **Multi** [Boo05b, Nem03]. **Multi-** [Nem03]. **Multi-Way** [Boo05b]. **Multidimensional** [ME05, Ano03-29, Bur08a]. **Multilevel**

[GP06, Gel06, Lip05, Ano06w, Zie02-34]. **Multimedia** [Mul04]. **Multimodel** [Ano03y]. **Multiple** [HG06, HBL03, JW02, KBS08, ML01, MX08, YS05, Zie00-34, LCdC06, Zie00-34, Zie04l]. **Multiple-Method** [HG06]. **Multiple-Response** [MX08]. **Multiple-Target** [JW02]. **Multiresponse** [Hec01, Lan01]. **Multiscale** [GCS06]. **Multistage** [Buk09, But04, LT09, ZDCS03, ZTL08]. **Multistate** [Bre06]. **Multistratum** [TG01]. **Multivariable** [Key01]. **Multivariate** [Ahm08g, Ano03-45, Ano03x, Ano04e, Ano05h, Ano06-37, AS01, AL03a, Ars05, Atk05, BBJK04, Boo00, Boo03, Cho06, CS02, DS06, Dup05, FJ08, FG06, GV07, HMT07, HMT08, Hec05, Hub01, JP01, Kat03b, Kat04a, Kat04b, Ken02, LLBN08, Nem00, PP01a, PP01b, Pol01, QH01, Qu07a, QD04, Rag01, RF05, RW01, RMGR09, RVVA04, ST06, SJ02, TG00, TTL07, TJ09, ZH06, Zie00b, Zie01-31, Zie02o, Zie04a, Zie04f, ZTW07, BF08, Ano05-57, Ano04p, Ano05-32, Bab02a, Bay02, Con05, Edg04, Kuh05b, LaL01, Qiu00, Qu07b, Wil05, Zie00-35, Zie00-36, Zie01-28, Zie02e]. **Multiway** [Esm09a, Esm09b]. **Mun** [Von06]. **MUNDA** [Bur08a]. **Murdoch** [Hly09a]. **Murray** [Ke06]. **Murrell** [Gun06]. **Murtagh** [Hec07]. **Murthy** [Ano03-50, Dog04, Olw01b]. **Musicology** [Zie04w]. **Muth** [Zie01e]. **Muzaffar** [Neu08c]. **MVT(R)** [Ano05m]. **Myers** [Zie02-31, Zie02-36, Smi01]. **Myerson** [Ano06y]. **Myles** [Ram00b, Ano05-56]. **Myunghee** [Ano04y].

N [Ahm08g, Ahm09, Ano03p, Ano03-28, Ano03-50, Ano04v, Ano04j, Ano05s, Ano05u, Ano07e, Ano08n, Ano09d, Boo09b, Cha04, Che01a, Che02a, Chi07, Den00, Dog04, Hor09b, Hut04, Kar07e, Ke09a, Nem03, Oli09b, Olw01b, Ran03, Rob02, Sea09, Str01, Zie00y, Zie00z, Zie00b, Zie00-43, Zie01-28, Zie01-27, Zie01-34, Zie03a, vB02]. **Nachlas** [Hey06]. **Næs** [Zie04a]. **Nagaraj** [Lum01]. **Nagaraja** [Cha04, Sea09]. **Naik** [Zie00b, Zie01-28]. **Nan** [Ano05e]. **Nancy** [Ano03-42, McC08]. **Nando** [Sar03]. **Nandram** [Zim01]. **Nanny** [Gho07]. **Nanotubes** [Kva08]. **Narayan** [Cab03]. **Nathan** [Ano06-42]. **Natural** [Cob00]. **Nature** [Jar08, Ano05-33]. **Nature-Inspired** [Ano05-33]. **Naumann** [Zie01m]. **Naus** [Zie02-39]. **Nearly** [CL07, Xu02]. **Nearly-Orthogonal** [Xu02]. **Needs** [Bar04]. **Neerchal** [Lum01]. **Neil** [Ano06-27, Boo03, Kal06, Sar03, Zie00-42, Zie01-39]. **Nekrutkin** [Ruk02]. **Nelder** [Ano07l, Gho08a]. **Nello** [Bre05a]. **Nelsen** [Ray00]. **Nelson** [Ano05-52, Esp06b, Ano05-52, Mee03]. **Ness** [Gup00]. **Nested** [HJM09]. **Network** [Bod02a, IM05, MBB05, Rao00]. **Networks** [Ahm08b, CGHL01, DLM$^+$07, Hea03, Hly07, KLM08, Li05, Liu09a, Mar03, Ped01, Qia02, Soy09, Ano05-33, Cas05, Cut00, Zie00-49]. **Neubauer** [Ano09a, Wlu06]. **Neuilly** [Bur00]. **Neuman** [Zie02-48]. **Neural** [Ano05-33, Cas05, IM05, Liu09a, Rao00, Zie00-49, Cut00]. **Neutron** [HTMW08]. **Newey** [Liu09b, Ord07a, Ord07b]. **Newman** [Zie02v]. **News** [Ste07]. **Newton** [Rum00]. **Next** [Ano05-55]. **Ng** [Kar07e]. **Ngai** [Qia07, Zie02-50]. **Niall** [Ano07l]. **Nicholas** [Ahm07c, Ano05g, Ano05-57, Dra04, Hec08, Mic01]. **Nicholls** [Zie00h].

Nichols [Ano06-36]. **Nicholson** [Zel05]. **Nickerson** [Fri05]. **Nicolo** [Lip07b]. **Niels** [Ano07u]. **Nielsen** [Ano06-43, Ahm08b]. **Nigel** [Bar09]. **Nikolaidis** [Ano06n]. **Nikolaos** [Ano08l, Ano09l]. **Nikulin** [Ano09l]. **Nil** [Sen06a]. **Nils** [Ros05]. **Nina** [Ruk02]. **Ninth** [Liu09b, Ord07a, Ord07b]. **Nishisato** [Ars05, Bur08a]. **Nitis** [Kat08a, Sar06]. **Nizam** [Key01]. **NJ** [Mai05]. **no** [Bri06, Buj06, Efr06, Hub06, IM02, Lan06]. **Noise** [KCM00, LSB06, PK05]. **Noisy** [HC00]. **Nolan** [Cha01a, Boo04b, Hey01]. **Non** [Li09]. **Non-Gaussian** [Li09]. **Noncentral** [Mee01]. **Nondetects** [Gat06]. **Nonhomogeneous** [BDNN04]. **Nonlinear** [Ano04-27, Ano09c, BK04, Bur08a, For08, Gan06, GJS09, HV07, Lu04b, PW01, Sen06b, Soy04, SMB01, Ano05-34, Cam01b, Liu06, Lu04a, Mur07, Sca02]. **Nonnormal** [RACH09]. **Nonorthogonal** [HK00, MS05]. **Nonparametric** [Ahm08c, Ano07i, Bar09, CHvdW06, Che03, Fot04, Fot07a, GG04, Gro00, Li06, Lom05, Lu04a, Nas01, Pol01, Ran03, Zie04i, ZTW08, Ano04q, Bak00, Gho03, Lor05, Lu07, Lu08, Ode00b, Qia00, Ram00b, Ste04]. **Nonparametrics** [Cas05, Zie00c]. **Nonquadratic** [FFG06]. **Nonregular** [CLY04, LLY03, LST07, XD05]. **Nonresponse** [Kar07c, Zie02-46]. **Nonstandard** [RACH09]. **Nonstationary** [COR08, Sca02]. **Nora** [Ano03-37]. **Norbert** [Zie00e]. **Norm** [Ano06-37]. **Norma** [Zie02-27]. **Normal** [Gui08, HME08, KMM08, UL07]. **Normal-Based** [KMM08]. **Normality** [LP06, Kap03, Sen05, Nel01]. **Normalized** [ŽH09]. **Norman** [Ano06-34, Ano07p]. **Northorn** [Ano06e]. **Note** [CHvdW06, CO01, Gui08, Ste09b, TJ09, UL07]. **Notz** [Den04]. **Novel** [Kal03]. **Nozer** [Aba01b, Gho08b]. **Null** [GS08]. **Number** [Bor00, McC04, MEM05, NM02]. **Numbers** [Ano06-38, GV03]. **Numerical** [Lar08, Gan06, Lip09, Mai05, Was02, Zel00]. **Nunnari** [Zie02-40]. **Nychka** [Zie01-49].

O [Alt03, AW01, Ano06-41, Bai04, Bar02, Sen06a, Zie02-44]. **Objective** [Ker03]. **Observation** [Coo00a, ZMW08]. **Observational** [Ano03-30]. **Observations** [SJ02, Zho01, Zie00o, BG06]. **Observed** [Pro00, Oli09c]. **Obuchowski** [Ano03-42]. **O'Connell** [Zie01i]. **O'Connor** [Rom03]. **Offen** [Chi06]. **Offset** [JS03, JC06]. **Ogden** [Gho01]. **O'Gorman** [Ahm04]. **Ohser** [Qiu02]. **Ojeda** [McC06c, Mic05]. **Okine** [Sen06a]. **Olea** [Zie00s]. **Oligonucleotide** [BH08, BCBS08a, BCBS08b, Gol08, HB08, Jon08, KL08]. **Olive** [Ami04]. **Oliver** [Zie01u]. **Olivia** [Zie02c]. **Olivier** [Ano07g, Nag06]. **Olkin** [Ahm08c]. **Olofsson** [Lip06a]. **Olsen** [Sau02b]. **Olson** [Zie02u, Ano03-46, Ano06-44, Zie00-30, Zie01-51]. **Olwell** [Umb01]. **Oncology** [Zie04-27]. **One** [BG06, FKQS01, FW06, KM04, LLI05, Zie02t]. **One-** [LLI05]. **One-Factor-at-a-Time** [FW06]. **One-Sided** [KM04, BG06]. **One-Way** [FKQS01, KM04, LLI05]. **Operating** [Cla04b, JLSZ08, JW04b]. **Operational** [Sen07]. **Operations** [Hly09b, Oli09d]. **Optical** [GLV02]. **Optics** [Per04]. **Optimal** [Ano06h, BC07, CW02, CA06, DM08a, FM04, GD03, GV03, KJ09, Ke05, KD05, LL03, LLY03, MNS04, Mit00, NCB04,

NC08, Pas03, RHOYL06, XCW04, ZZJ07, Gri04]. **Optimality** [BV01]. **Optimization** [CHCFC04, Den06, Hes04, JW04a, LM04, ME04, Miy04, NW04, RdC05, Sud04, TGLG09, Alt01, Ano06t, Gho09, Olw01b, Zie01-43, Zie02d, Gru05, Zie01-29]. **Optimum** [Atk05, DM08b, Iye02, Hor09b]. **Order** [BSC09, CA06, GD03, PKV07, RF05, Sea09, Zie00y, Zie00z, Cha04]. **Ordered** [GP01]. **Orders** [Car07a, Ano08q]. **Ordinal** [LLBN08]. **Ordys** [Bar08c]. **O'Reilly** [Zie00h]. **Oriented** [Zie00-32]. **Origin** [Li05]. **Origin-Destination** [Li05]. **O'Rourke** [Ano06-37]. **Orthogonal** [CL07, LLY03, Mar05, MMM08, Xu02, ZZJ07, Den00]. **Oscar** [Ano08f, Xu06]. **Other** [Ano03a, Ano08p, Bar05, CHCFC04, Mee03, Oli08, Won04]. **Ott** [Ano05j, Kim05, Wlu06, Kar07b]. **Otto** [Zie01l]. **Outdoor** [CLM04]. **Outlier** [Hub01, PP01a, PP01b, RW01]. **Outliers** [JP01]. **Output** [Ano08o, Dri06, MBC00]. **ová** [Oli07]. **Oxford** [Ano04-30]. **Ozone** [Dup05].

P [Aba01b, Ano03r, Ano03y, Ano04l, Ano05-57, Ano05-56, Ano05-31, Ano05-29, Ano05-50, Ano06h, Ano06-40, Ano07p, Boo08, Cha01b, Che01b, Cob04, Con00, Den06, Eas07, Glo05, Kar07a, Kib07, Kim00, LZ02, Lip09, Liu07a, Lum01, Mai05, Mic03, MR00, Nel00a, Ode00a, Pig06, Ran03, Rav04, Sar00b, Soy09, Str01, Wal05, Yeh07, Zie00u, Zie00-40, Zie00-32, Zie00l, Zie00h, Zie01-41, Zie01-40, Zie01g, Zie01w, Zie01f, Zie02-48, Zie02-30, Zie04y]. **P.-T** [Zie02-30]. **Padhraic** [Owe04]. **Pahkinen** [Ano05-38]. **Paik** [Ano06-33, Ano04y]. **Pairs** [FM04]. **Palazoglu** [Neu08a]. **Palit** [Ano06j]. **Palmer** [Zie02u]. **Palta** [Ano04r]. **Pan** [Kuh03]. **Pande** [Zie02-48]. **Pandu** [Lew04]. **Panel** [Ano06-39, SBF$^+$08]. **Pang** [Cab09]. **Panjer** [Ano06v, Sen07]. **Paolo** [Boo09c, Owe04, San05]. **Paper** [Mal06, Bri06, Buj06, Efr06, Hub06, Lan06]. **Papers** [Ano07r, Ano07s, Ano07q, Gho07, SS07, Ahm09]. **Paradigm** [Kaf03]. **Parallel** [Ano08h, ZC06]. **Parameter** [Alt01, Ano09c, BS03, Bur04, DW06, GJS09, JW02, Jos03, KJ09, LLBN08, PW01, QD04, ZZJ07, ŽH09, Mam08]. **Parameters** [AK04, BKG09, DM08b, HSR09, JCR01, LHB$^+$02, LP06, Qia05, CJFR05]. **Parametric** [Ahm08c, Ano05-35, Ano07i, AB04, Bed00, JM01, Lu04a, Nas01, Sco01, SP07, SMB01, Zie04i, DGS07]. **Pareto** [CS01, ZS09]. **Park** [Zie01-43]. **Parmigiani** [Ano03-49, Zie02-33]. **Parr** [Zie02c]. **Part** [Che06, Zie00u, BH00]. **Partial** [CL09, GM01, MS00]. **Particular** [DP02]. **Pass** [Boy01]. **Pass-Fail** [Boy01]. **Past** [Kaf00c]. **Pat** [vB02, Esp07]. **Path** [RWZF04]. **Patricia** [Nem02a, Sin08]. **Patrick** [Ano03h, Ano05l, Neu09b, Rom03, Zie05b]. **Pattern** [Bag05, BLC01, Bre05a, Dav03, Liu09a, Sea05, TGLG09, Ano06x, Bar02, Nea07]. **Patterns** [AL03a, LH02, SA08, Lin02, Sym05]. **Paul** [AW05, Ano03-51, Ano03r, Ano03-39, Ano03-30, Ano06q, Ano06-38, Ano08m, Boo05b, Cla04a, Con04, Gun06, Joh00, Kat04a, Liu02, Lu08, Qia02, Qiu00, Qu07a, Sch04, Sen06b, Sho05, Wei03, Zie00r, Zie00-31]. **Pauler** [Ye03].

Paulo [Sin09]. **Pause** [Zie00-45]. **Pavlov** [Sen00]. **Pawitan** [Gho08a, Sau02a]. **Pearl** [Zel01]. **Pearn** [Ahm08h]. **Pearson** [Fot01]. **Peck** [Ano07j, Gra02, Sau02b, Min02]. **Peel** [Sha02]. **Pei** [Ano05-54, Zie00j]. **Peihua** [Lor06]. **Peña** [O'N03, Zie01a, Zie01h]. **Penalized** [LS05, ME05]. **Peng** [Mye09c]. **Pensky** [Sha04]. **Pepe** [Ano05-51]. **Percival** [Che01c]. **Percy** [Hly09b]. **Performance** [Bar08c, CE02, Hly07, JCR01, Law01, LPP00, Neu08a, RACH09, Zie02-51]. **Perkins** [Bur09b]. **Permutation** [Bab02a, Ano05-35, Ano08m, Liu02, Zie01-30]. **Perspective** [And08, CL03, Gho08b]. **Perspectives** [Con04, Ye05]. **Persson** [Liu09b, Ord07a, Ord07b]. **Perturbation** [Ruk01]. **Pesarin** [Bab02a]. **Peter** [Ano03s, Ano03h, Ano03k, Ano05-46, Ano06m, Ano09i, Bar02, Bar09, Bur03, Cha01c, Das07a, Esp06b, Fin02, Gan02, Ke05, Lip06a, Mag00, Mai08, Ros05, San03a, Sca02, Sen02, Sho04, Sin09, Sym05, Zie00-34, Zie01-29, Zie02-48, Zie02b]. **Petre** [Ano05z]. **Petrochemical** [BBJK04]. **Petroleum** [Zie00q, Zie05b]. **Petruccelli** [Zim01]. **Ph** [Ano03k]. **Phaedon** [Ano06p]. **Pham** [Liu07b]. **Phan** [Zie00-37]. **Phan-Tan-Luu** [Zie00-37]. **Pharmaceutical** [KS07b, Zie00j, Zie01e, Zie02q, Che08c, Zie00-37]. **Phase** [MW04, ZTL08]. **Philip** [Ano05-41, Kat09, Ken02, Ped01]. **Philippe** [Lu07]. **Phillip** [Ano03f, Ano05-35, Ano06z, Ano06u, Cha00, Sin07, Zie01-30, Zie02-35, Zie02r]. **Phipps** [Lip07c]. **Phiroz** [Ano06x]. **Physical** [Ano09b, Pic05, RWH+04]. **Physics** [GLV02]. **Picek** [Oli07]. **PID** [Neu08b]. **Pieces** [Bak01]. **Piecewisely** [Qiu04]. **Piegorsch** [Ano06g, Zie02y]. **Pierre** [Cob00, Owe04, Zie00r]. **Piersol** [Cha01c]. **Pieter** [Esm09a, Esm09b]. **Pinheiro** [Zie01z]. **Pintilie** [And08]. **Pitting** [FHR06]. **Plackett** [KB05, MS01]. **Plackett-Burman** [KB05]. **Plain** [Bri03]. **Plan** [Kun08]. **Plane** [Fam03]. **Planning** [Alt01, SEM09, ZM06, Rut05]. **Plans** [Ano05-52, BSG00, Hem02, LL03, LLY03, NCB04, PM03, Pas03, Pas06]. **Plant** [Hec01, Boo04a]. **Plot** [BS03, GV03, Gui08, Ke05, KCV02, MB04, PKV07, RACH09, KB05]. **Plots** [GV03, MS00, SNS07]. **Plotting** [Nel00b]. **PLUS** [Utl05, Zie04c, Zie00-42, Ano03-46, Ano06-44, Fot07b, Kus03, Lum01, Zie01-51, Zie01-27, Zie01z, Zie02i, Zie02n, Zie05a, Bur07, Zie00-33]. **PLUS(R)** [Ano03z, Ano06u]. **Poduri** [Che02b, Maz02]. **Point** [CCD09, COR08, Sca04, Sca07, Sym05, ZH06, ZTL08]. **Poisson** [Bru00, BDNN04, WT09]. **Polansey** [Oli09c]. **Polhemus** [Zie00-42]. **Policy** [Zie01-32]. **Politics** [So01]. **Politis** [Str01]. **Pollution** [Mye09c]. **Polynomial** [BGW03, BSC09, DWG09, GPR05]. **Pooling** [GP06]. **Pools** [RHOYL06]. **Popovic** [Ano06j]. **Population** [Ano04r, BG06]. **Populations** [Zie00-40]. **Porous** [LHB+02]. **Portfolio** [Ano06t]. **Possible** [Mil05]. **Post** [VB09]. **Post-Fractionated** [VB09]. **Poursat** [Ano04-27]. **Power** [Ano03-48, MV05]. **Powerful** [Zha06]. **pp** [Zie01-52]. **pp.** [Mai05, Zie05b]. **Prabhakar** [Ano03-50, Dog04, Olw01b]. **Practical** [And08, Ano05-43, CM08, Cha00,

Che08c, Chi06, DS00, Hec09, Ker02, LSW09, McC00, Sar00b, She00, Sta00, WW00, Yat02, AW05, Ano05-36, Ano05-39, Ano05-37, Ano05-38, Cob02, Gib01, Gro00, Mye01, Nas02, Neu08b, Rom03, Rut02, Sar02, Zie00-38]. **Practice** [Ano04l, Bak01, Gun00, Sar00b, Zie01-50, Zie01w, Zie04y, Ano06-28, Kar07f, Lu07, Ray03b, Sar03, Was05, Zie01i, Zim00]. **Practitioner** [Rum06, Was01]. **Practitioners** [Ano08e]. **Preben** [Was04]. **Precedence** [Kar07e]. **Precedence-Types** [Kar07e]. **Predict** [MEH09, ZCC08]. **Predictability** [Wik05]. **Predicting** [GPR05, dCGM05, Ano08n]. **Prediction** [BG04, Bur03, FL07, HJMW04, HSNB09, KMM08, LWS03, NM02, ÖBMT02, Olw01b, BG06, Ano05-51, Ano09m, Ode00b, Lip07b]. **Predictions** [McC03c]. **Predictors** [HBL03, MBG07]. **Prentice** [Geo03]. **Preparation** [Nas08]. **Prescott** [Zie00a]. **Presence** [Kun08]. **Present** [Kaf00c]. **Preserving** [KFV+07]. **Press** [Gru02, Lip09, Ker03]. **Presser** [Ano05-29]. **Pressure** [FK00]. **Preventive** [Tor01]. **Price** [Moo01]. **Primer** [Ano05n, Nem02a, Che08a, Hor09c]. **Principal** [HRV05, HN03, Mar05, Ano03-31]. **Principles** [AW01, Ano04s, Gri04, Jar09, Ker03, Ray03b, WLLZ07, Hem02, Dok08, Zie01-31]. **Prior** [BC07]. **Priors** [JD07]. **Privacy** [KFV+07]. **Privacy-Preserving** [KFV+07]. **Probabilistic** [FJ08, Fri05, Gri07, Hey06, Kat09, Soy09, Zie00-43, Bas02, Ped01, San07]. **Probabilities** [HME08, WT09]. **Probability** [AB03, Ann03, Bri04, Gui08, Jos04, KL02, LPP00, Mam09, Pic09, Sau05, Sau06, SC00, SNS07, Yeh05, Yeh07, Zie01-38, Zie02p, Ano03-35, Ano05n, Oli09a, Zim04, Ano03-32, Ano06y, Bre02, Cab08, Esm05, Esm06, Fot07c, Hen01, Hly09c, Ke08, Kim04, LaL04b, Lip06a, McC03b, Ng09, Per04, Qia01, San08a, Taa02, Zie04m]. **Probablity** [Neu09a]. **Problem** [Per04, QD04, Sar05, Ste00b, Zie02-51, MR01]. **Problems** [CHCFC04, DP02, HK00, HME08, Kaf01c, WM02, Cha05, LH06]. **Procedure** [BGW03, BGMS03, QH01, Qiu04]. **Procedures** [Ano07i, Hem02, JM00, LSB06, Neu01, Zie00-46, Cha01c, Nas01, Zie04i]. **Proceedings** [Zie02b]. **Process** [Ahm08h, Ano06-36, AK04, BBJK04, Bar01, BO09, Bel01, BGMS03, Cah06, DM08b, Edg04, Fri00, Gho09, HZ05, JLH+06, JWT+02, Kaf03, KML04, KCV02, LT09, LEH03, LBH+06, Mor04, Nel01, Neu01, Neu03, Neu08a, Pla01, Pol01, QWW08, RdC05, RS06, Ste00a, TH05, Var00, YM00, Yat02, ZH06, Zie01-43, Zie02h, Zim02, vN02, Aba01a, Zie04p, Bar08c, Tob03, Wlu06, Zim00]. **Processes** [Ano04j, AS01, AL03b, AL03a, BE03, BGMS03, BDNN04, But04, CE02, Che06, FFG06, Kim04, Liu07a, McC05b, Ode00b, Pic05, Sca04, Whi04, ZZ07, ZDCS03, ZTL08, ŻH09, dC02, Ano07s, Buk09, Cab03, Esm05, Fot07c, Fot09, Lip06a, McC06a, Sca07]. **Processing** [Liu06, Lor06, Zie01n, Bab05, Cab06, MM00, Sca02]. **Procrustes** [Cha05]. **Producing** [JS07]. **Product** [Ano03a, Ano05-58, KT05, Mee03, MEH09, vN02]. **Production** [BBJK04, YM00]. **Productivity** [GM01]. **Products** [CLL09]. **Professionals** [Ano04u]. **Professor** [Ano07l]. **Profile** [SMB01]. **Profile-Based** [SMB01].

Profiles [KML04, MW04, ZTW07, ZTW08, Mul08]. **Programmer** [Hol08, San03b]. **Programming** [Ano06-40, Fre00, Hly09a, Mur07, Zie00-41]. **Progressive** [Kun08, NCB04]. **Progressively** [BSG00]. **Projection** [BBJK04, LST07, XD05]. **Projective** [XCW04]. **Promislow** [Nku07]. **Pronzato** [Zie00-32]. **Properties** [CJFR05, HWY02, LST07, WM05]. **Proportion** [GHB+07]. **Proportional** [JWT+02]. **Proportions** [Ano04y, Esp06b]. **Proposed** [BN01]. **Proschan** [Che07]. **Proximity** [Lip07c]. **Psychology** [Fri05]. **Public** [Zie01g, Zie01-32]. **Pugesek** [Ano06-31]. **Purohit** [Ahm07b]. **Purposes** [Bar08b]. **Putting** [Bak01]. **Pythagorean** [Con04]. **Pyzdek** [All01, Zie00-51].

Qi [Con01]. **Qi-Man** [Con01]. **Qing** [Ruk01]. **Qiu** [Lor06]. **Qiwei** [Lu04a]. **Quadratic** [PYC07, YS05, PDDL02]. **Qualification** [Neu01]. **Qualimetrics** [Zie00u]. **Qualitative** [HSNB09, QWW08]. **Quality** [Ahm08h, Ann06, Ano03-36, Ano03-43, Ano05-27, Ano06-35, Ano09a, Bai07a, BH08, Bar07c, Bay02, Bod02b, Bre01, BCBS08a, BCBS08b, Fri00, GP01, Gol08, HB08, Hof00, Hor06, Jon08, KL08, Kuh05b, LC00, Maz06b, McC08, Mit02, Neu03, O'N03, Spi07, Umb01, Wlu06, WM05, Yat01, Zie00-47, Zie00-42, Zie01v, Zie01-40, Zie01h, Zie02-30, Zie04-27, Zie04u, Zim02, Ano03r, Sta00, Zie01-55, All01, Ano05-40, Bar04, Bru00, Esp07, HL06, Rob02, Ste00b]. **Quality-Control** [LC00]. **Quantification** [Zie03b]. **Quantify** [BCL+09]. **Quantifying** [Smi01]. **Quantile** [Glo01, Lom05, ZCC08, Lip06b]. **Quantitative** [HSNB09, Mul02, QWW08, Ano04r, Ano05-41]. **Quantum** [Ale02]. **Quenneville** [Zie01-35]. **Questionnaires** [Ke09a, Ano05-29]. **Questions** [Fam03]. **Queueing** [Fre00, Hly07]. **Queues** [Ode00a]. **Queuing** [McC03b].

R [Ann03, Ano03-27, Ano03-48, Ano03w, Ano03p, Ano03u, Ano03-41, Ano03n, Ano03y, Ano03k, Ano03-30, Ano03-50, Ano04j, Ano04k, Ano05i, Ano05o, Ano05y, Ano05j, Ano05u, Ano05-57, Ano05-56, Ano06-33, Ano06i, Ano06-39, Ano06s, Ano07k, Ano07x, Ano07p, Ano08p, Ano08e, Bab02b, Bin01, Bur09a, Cab00, Cam02, Car07d, Car07a, Che01a, Che02b, Dok08, Esp06b, Gat06, Geo00, Gho01, Gra00, Gun04, Hin06, Hor09b, Jen09a, Kaf03, Kar07b, Kar07d, Kat03a, Kib07, Kim05, Kus02, Kus06, Laz03b, Liu06, Liu07a, Maz02, McC00, McC08, McC06a, Mic03, MR00, Mul02, Mye09c, Nem04, Oli08, Olw01b, Per04, Pla01, Qia01, Rum00, Sin01, Smi06, Utl05, Von03, Wal05, Was01, Weh04, Wlu06, Zie00p, Zie00x, Zie00y, Zie00z, Zie00w, Zie00-30, Zie01-55, Zie01-46, Zie01g]. **R** [Zie02-48, Zie02t, Zie02-49, Zie02g, Zie02-29, Zie02-40, Zie04c, Zie04z, Zie04d, Zim00, Ano06e, Ano06u, Ano09i, Chi07, Hec07, Hly09a, Mye09a, Ng06, Ng09, Oli07, Pic09, Rob05, San03a, Gun06]. **R&D** [Gol04]. **R&R** [Maz06a]. **R.-D** [Ano08p, Cam02]. **R/S** [Ano06u]. **R/S-PLUS(R)** [Ano06u]. **Rabe** [Ahm08a, Fri01, Lip05, Zie02n]. **Rabe-Hesketh** [Ahm08a, Fri01, Lip05, Zie02n]. **Rabinowitz** [Sau06]. **Radhakrishna**

[Bor01]. **Radial** [Qia02]. **Radmacher** [Ano05-54]. **Rae** [Rum00]. **Rafael** [Ano03-49]. **Raftery** [Zie02-45]. **Raghavarao** [Ste04]. **Rahul** [Loe07]. **Rainer** [Ano07g]. **Rajesh** [Alt06, Jia03]. **Ralph** [Che08c, KS07b]. **Ramachandra** [Cam01a]. **Ramaswami** [Bur01b]. **Ramon** [Moo03, Zie01-33, Zie04n]. **Ramsay** [Alt03, Ano06-41]. **Rand** [Ano05y, Bab02b, Nem04]. **Randall** [Bak00, Fin05, Zie00-34]. **Randolph** [Ano05z]. **Random** [BK04, BLC01, BG04, BG05, CE02, Dra04, Esm05, FK00, Fot07c, Gho08a, GB01, GHB$^+$07, Hen01, Iye02, Kim04, KM04, LHB$^+$02, LLI05, McC06c, Mic05, Pas03, Pic06, SB04, ŽH09, Cha01c, Ano09j, Bor00, McC04, Sea05]. **Random-Coefficients** [BK04]. **Random-Effects** [BG05, GB01]. **Randomization** [Ano03-33]. **Randomized** [San07]. **Randy** [Ano05-37, Ste07]. **Range** [ŽH09, Pfa04]. **Ranjit** [vN02]. **Rank** [MY08, QH01]. **Rank-Based** [QH01]. **Ranked** [Zha05]. **Rao** [Ano06s, Bor01, Cam01a, Zie01-46, Ano03p, Ano04v, Ano04j, Ano04k, Ano05u, Ano06i, Che02b, Fot09, Maz02, Sin01, Zie00x, Zie00y, Zie00z, Zie00w, Zie01g]. **Rasmus** [Ano06-43, Boo05b]. **Rässler** [Ano04x]. **Rate** [KBS08, LT09, Pro00]. **Rate-Adjusted** [LT09]. **Rater** [Von06]. **Rates** [Ano04y, Esp06b, GV07]. **Ratio** [CM08, DS00, Zha06]. **Ratner** [Ano04z]. **Ratto** [Che08a, Was05]. **Rausand** [Zie04x]. **Ravindra** [Zie00b, Zie01-28]. **Ray** [ASW$^+$06, Ano05i]. **Raymond** [Fri05, Zie02-31, Zie02-36]. **Rayner** [Che03]. **Reactor** [LWS03]. **Read** [Zie00m]. **Real** [Ano03-27, Sar06]. **Real-World** [Sar06]. **Really** [Gol07]. **Reasoning** [Ahm08f, Bai04, Zel01, Ano03l, Fri05]. **Rebecca** [Zie04r]. **Receptor** [CS02]. **Recipes** [Lip09]. **Recognition** [Ano06x, BLC01, DJ07, Nea07, Dav03, Liu09a, Sea05]. **Reconciliation** [Kar07a]. **Recovery** [HC00]. **Recurrence** [ZMW08]. **Recurrences** [Ano03a, Mee03]. **Recurrent** [Ano03a, FL07, SP07, Mee03]. **Recursive** [Sán06]. **Redmond** [Zie02w]. **Reduced** [BV01]. **Reducing** [McC06a]. **Reduction** [JLH$^+$06, Lin02, Zie01-28]. **Reese** [Hor09a]. **Reference** [Tom07, Yat01]. **Refresher** [Ano07k]. **Reginald** [Zie00h]. **Region** [ZCC08]. **Regions** [BG05, GD03, BF08]. **Register** [Bar08b]. **Register-Based** [Bar08b]. **Regression** [Alt02, Ano03v, Ano05f, Ano06q, Ano07j, Bak00, BSC09, BF05, CHCFC04, Coo00a, Coo00b, CO01, GLM07, GB01, GG04, Gra00, Gra02, Gun00, Gup00, GPR05, HBL03, Hec08, HV07, Hey09, HK00, HN03, JQ09, Key01, LN06, Lor06, Mar05, ME05, McC03c, Oli02, Oli03, Oli05, OH05, Pan00, Peñ05, Por02, Qiu04, RA00, RVVA04, SC04, SB04, SMB01, YW05, Zie00-31, ZTW08, Ami04, Ano03-44, Ano04-27, Ano07i, Con02a, Li06, Lip06b, Mal05, Soy04, Wal05, Zie01-33, Zie01-37, Zie04c, Zie06, Ano05-42, Ano07n, Cab00, Gol06b, Gun03, Moo01, Ray03a, Wal03, Zie04n]. **Regressions** [FW00]. **Regularized** [Qia02]. **Reid** [Che01a, Con00]. **Reilly** [Zie02-32]. **Reiss** [Ano08p, Cam02]. **Reiter** [Lip07a]. **Rejoinder** [BCBS08b, Wil08b]. **Rekab** [Neu08c]. **Related** [Ano07o, Ano09k, HN03, Rag01, Ruk02, SC00, Sin06, Won04]. **Relating**

[Nel00a]. **Relationship** [HJMW04, Pas06]. **Relationships** [CR06, Zie00o]. **Reliability** [Ann03, Ano03-32, Ano03-50, Ano06n, BSG00, Bar08a, BE03, Bru00, CLL09, Dog01, FK00, Gat02, Gri04, Ke07, Ke08, KMM08, Law00, McC03b, MEH09, MSM03, Ng08, RLR06, Rom03, Sen00, Tob00, WM02, Zie01-41, Zie04x, CFP08, MN06, Ano03p, Ano08l, Din05, Hey02, Hor07, Hor09a, Hua00, Zie00-43, Zie04z, Ann06, Gho08b, Hey01, Hey06, Hil00, Joh00, Ke07, Mye05a, Olw01a, Olw01b, Sta04, Tor01, Zie02f]. **Reliable** [Ahm08f]. **Remacre** [Ano05s]. **Remaining** [DM08a]. **Reminiscences** [Dok09]. **Rencher** [Rut09, Ano03x, Bur01a]. **René** [Nas02, Yu07b, Zie05a]. **Renewal** [LEH03]. **Repairable** [LEH03, Zie01-41]. **Repairs** [Ano03a, Mee03]. **Repeated** [Gho05, Gol06b, Ken03, Kia01]. **Replication** [CL09]. **Report** [Kaf00b, Kaf01a, Not02, Not03b, Not04, Sit05, Sit06, Sit07, Ste08b, Ste09c]. **Representation** [Cab09, Lip07c]. **Requirements** [MEM05, Ke07]. **Resampling** [Ano06u, Lou01, Ano06z, Cha00, Hut04, Zie02-35]. **Research** [Ahm06, AW01, Ano03j, Ano05-58, Hly09b, KT05, Sen06a, Ano04o, Ano04-28, Ano04-31, Bre05b, Ke09a, Liu04, Nem02b, Zie00e]. **Researcher** [Mor05a]. **Researchers** [Ano08e]. **Reserves** [Ano06p]. **Reservoir** [Ano05r]. **Residual** [MS00]. **Residuals** [YM00]. **resolution** [LM02]. **Resources** [Cob00, RS04]. **Response** [ACBJ09, ALKP02, Ano05-42, BV01, CO01, FM04, GD03, GD04, JW04a, JW04b, Khu06, LM04, LC00, MX08, MLC09, ME04, Miy04, Mor00a, MBDD09, NW04, PP01b, QD04, RF05, Rya08, Sen06b, Sud04, TG01, WKT$^+$03, YM00, YS05, Ano07p, Ano07o, Zie02-36]. **Responses** [Atk05, FHR06, RACH09, SX07]. **Restrictions** [DP02]. **Results** [Ano05m, MEH09, Zie02h, Zie00-28]. **Reuven** [Boo08, Den06]. **Review** [Aba01b, Aba01a, Ahm04, Ahm06, Ahm07b, Ahm07a, Ahm07c, Ahm08a, Ahm08d, Ahm08b, Ahm08g, Ahm08c, Ahm08f, Ahm08e, Ahm08h, Ahm09, Ale01, Ale02, All01, Alt01, Alt02, Alt03, Alt06, Ami00, Ami04, AC02, AW01, AW05, And08, Ann01, Ann03, Ann06, Ano03i, Ano03m, Ano03r, Ano03-27, Ano03-48, Ano03-36, Ano03-33, Ano03-35, Ano03w, Ano03p, Ano03q, Ano03-40, Ano03-34, Ano03z, Ano03-45, Ano03t, Ano03u, Ano03g, Ano03x, Ano03v, Ano03s, Ano03-28, Ano03-39, Ano03-41, Ano03-42, Ano03o, Ano03f, Ano03l, Ano03-44, Ano03n, Ano03h, Ano03y, Ano03k, Ano03-29, Ano03-30, Ano03-37, Ano03j, Ano03-46, Ano03-43, Ano03-47, Ano03-38, Ano03-31, Ano03-32, Ano04l, Ano04-30, Ano04-29, Ano04e, Ano04n, Ano04v, Ano04s, Ano04t, Ano04i, Ano04j, Ano04w, Ano04z, Ano04m]. **Review** [Ano04r, Ano04h, Ano04q, Ano04-27, Ano04g, Ano04k, Ano04y, Ano04f, Ano04u, Ano04p, Ano04o, Ano04-28, Ano04x, Ano05v, Ano05-46, Ano05i, Ano05f, Ano05-32, Ano05-42, Ano05-27, Ano05-34, Ano05q, Ano05o, Ano05-36, Ano05k, Ano05-43, Ano05t, Ano05-35, Ano05y, Ano05g, Ano05j, Ano05-44, Ano05-47, Ano05r, Ano05s, Ano05m, Ano05x, Ano05-49, Ano05n, Ano05-30, Ano05z, Ano05p, Ano05-40, Ano05w, Ano05-33, Ano05-39, Ano05-41, Ano05u, Ano05-45, Ano05-31, Ano05-28, Ano05-37, Ano05-48, Ano05l, Ano05e, Ano05-51, Ano05-38, Ano05-29, Ano05-50, Ano05h, Ano06-33, Ano06w, Ano06t, Ano06-34, Ano06g, Ano06j, Ano06x, Ano06r,

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S [Ahm08a, Ann06, Ano03-49, Ano03-47, Ano04l, Ano04-27, Ano06k, Ano06f, Ano06-40, Ano07w, Ano07v, Ano07n, Ano08n, Ano09f, Ars05, Bar05, Bur09b, Cab09, Cha01c, Che02b, Che08a, Das04, Das07b, Den00, Esp06b, Fri05, Glo06, Gre04, Gru02, Hem02, Hes02, Hin05, Hor09a, Hut04, Kat03b, Ken03, Ker03, Lu04b, Maz02, McC03b, Moo01, Mur07, Nem03, Nku07, Oli08, Sea01, Sta04, Tob00, Utl05, Zie00u, Zie00-40, Zie00x, Zie00w, Zie01j, Zie01-51, Zie01-50, Zie01r, Zie01y, Zie01a, Zie01z, Zie01k, Zie01w, Zie02-48, Zie02i, Zie02j, Zie02o, Zie02n, Zie04c, Zie04y, Zie04g, Ano06-41, Ano03z, Ano03-28, Ano03-46, Ano06-44, Bur07, Fot07b, Kus03, Lum01, Nas02, Zie00-33, Zie01-51, Zie01-27, Zie01z, Zie02i, Zie02n, Zie05a]. **S-PLUS** [Utl05, Zie04c, Ano03-46, Ano06-44, Fot07b, Kus03, Lum01, Zie01-51, Zie01-27, Zie01z, Zie02i, Zie02n, Zie05a, Bur07, Zie00-33]. **S-PLUS(R)** [Ano03z, Ano06u]. **Saar** [Huz03]. **Safety** [Ann06]. **Sahai** [Mat01, McC06c, Mic05]. **Saibal** [Sar06]. **Saisana** [Che08a]. **Saito** [Mar06]. **Sall** [Ano05-28, Ano08j]. **Sallie** [Ano08l]. **Sally** [Zie01-32]. **Saltelli** [Che08a, Was05, Zie01-36]. **Sam** [Qia00, Zie00-27]. **Samaradasa** [Gho05, Lit01]. **Sample** [CHvdW06, CG09, LSW09, MEM05, TTL07, TJ09, Van02, WW00, Zha06, Zie00k, Ano04s, Con04]. **Samples** [BKG09, GHB$^+$07, VD07, dCGM05]. **Sampling** [Ano05i, Ano09a, BSG00, Bru00, Gho02, Hem02, Kla01, LaL04a, MB06, Nem02a, Pic05, RSS02, RS04, SC00, Smi01, Zha05, Kar07b, Zie00-35, Maz02, Mye09b, Zie00-40, Zie00-39, Zie02-38]. **Samprit** [Ano07n, Moo01]. **Samuel** [Ahm08h, Ano06-34, Sha04, Zie00m, Zie04t, Zim00]. **Sanchez** [Ano06r]. **Sanchez-Vila** [Ano06r]. **Sandra** [Jen09b]. **Sanford** [Gra00, Mal05]. **Sanjeev** [Ahm08f]. **Santner** [Den04]. **Sarabia** [Boo09b, Rao01]. **Saris** [Ke09a]. **Sarjinder** [Car07c]. **Särndal** [Kar07c]. **SAS** [Ano08o, Cab04, Gun03, Hol08, Hor09c, Sin08, Ano06-40, Ahm08g, Ano09f, Hor09b, Nas08, Utl05, Zie02j, Ano08o]. **SAS(R)** [Ano03j, Ano06-37, Ano06-40, Che08c, Chi06, Jen08, Jen09a, LaL09, San03b, Van04, Zie00-31, Zie00b, Zie01-28, Zie01j, Ano06q, Ano03-34, Ano04t, Liu04, Moo03, Zie00-41, Zie01-33]. **Satisfaction** [Sin01, Bar04]. **Saul** [Lip09]. **Savage** [Zie00-27]. **Savazzi** [Ano05h]. **Scale** [GLM07, MBG07, MEM05, SM04]. **Scales** [CLL09, Mar05, WB05]. **Scaling** [Ano03-29]. **Scan** [PC01, Zie01-34, Zie02-39]. **Scans** [Che02a]. **Scanu**

[Kar07f]. **Schaalje** [Rut09]. **Schaeffer** [Ano03-37, Kar07b]. **Schafer** [Boo00, Hin06, She07]. **Schbath** [Das07b]. **Schechter** [Zie00e]. **Scheines** [Bur03]. **Scheme** [TH05]. **Schemes** [CW02, LT09, LC00, ZTW07]. **Scherer** [Ano06t]. **Schilling** [Ano09a, Wlu06, Yu07b]. **Schimek** [Zie01-37]. **Schinazi** [Taa02]. **Schlotzhauer** [Jen09b]. **Schoenberg** [Ano06-33]. **Scholes** [Cab08]. **Scholkopf** [Ano08n]. **School** [Car07c]. **Schott** [Kar07d]. **Schreiber** [Ano05-34, Cam01b]. **Schroeder** [Ale01]. **Schulze** [Neu01]. **Schumacker** [Fin05]. **Schwarz** [Zie00e]. **Science** [Ahm09, Bre02, Hly07, Hly09b, Kal03, Lu08, McC03b, Pic07, SS07, Zie01-44, Zie02-43, Esm06, Kat09, LaL04b, Mam09, Mul01, Qiu02, Rom06, San08a, Soy09]. **Sciences** [Ano07e, Zie00m, Ano03u, Boo05b, McC02, Neu05, Rag01, San08b, Wei03, Zie00-45, Zie01-49, Zie04m, Zie04t]. **Scientific** [Hes02, Jar09, Lip09]. **Scientist** [Ano07k, Mai05]. **Scientists** [Gru02, Jen02, Lar08, Mam08, Ram00a, Ano03-45, Ano03-32, Ano05g, Ano05-39, Ano09b, Esp06a, Fah07, Ke08, Mic01, Rut02, Sau05, Zie00s, Zie01u, Zim01]. **Sclove** [Zie04y]. **Score** [ST02]. **Scott** [Ano03-49, Ano03h, Ano04g, Esm05, LaL01, Zie01-36]. **Screening** [Ano08s, VDLB08, XCW04]. **Sean** [Ano03-34, Cab08, Esm06]. **Search** [Hes04, TGLG09, Bur03, Kat04b]. **Searle** [Von03]. **Seasonal** [LH02, Whi04, Zie01-35]. **Sebastian** [Gho03]. **Seber** [Oli03, Kok01]. **Second** [BSC09, CA06, GD03, PKV07, RF05]. **Second-Order** [BSC09, CA06, GD03, PKV07, RF05]. **Section** [HTMW08]. **Secure** [KFV+07]. **Security** [Glo06]. **Seeing** [Ano05-44]. **Segers** [Laz05]. **Seila** [Lew04]. **Seismic** [Ano00e, SBD98]. **SELC** [MWJ06]. **Selected** [Ahm09, Ano07r, Ano07s, Ano07q]. **Selecting** [KT03, MBC00]. **Selection** [Ano03-44, Ano03y, BGW03, BFL02, BC07, CL05, DT02, FM04, GG04, LWY02, LBH+06, LSB06, MR00, OH05, Oli09b, RSB09, SHY04, TVW05, YJL07, ZC06, FVB02, Ano09j, Cab00]. **Selective** [MNS04]. **Self** [Ano03v, Ano06-32, HMT07, SJ02, CFP08]. **self-dual** [CFP08]. **Self-Learning** [Ano03v, Ano06-32]. **Self-Starting** [HMT07, SJ02]. **Selvin** [Zie00-33]. **Semiconductor** [BLC01]. **Semiconductors** [HTMW08]. **Semifolding** [MP00]. **Semiparametric** [Ahm08c, FKQS01, Lor05, MSM03, YW05, Fok07, Wal05]. **Semiparametrics** [Ano07v]. **Sen** [Zie01g]. **Senn** [Ano04-31]. **Sennott** [Fre00]. **Sense** [Jar04]. **Sensing** [Che06]. **Sensitivity** [ACBJ09, CHCFC04, Che08a, DWG09, MMM08, Oak09, RCGD06, SMB01, Was05, Zie01-36]. **Sensor** [KLM08]. **Separation** [AL03a, Con05, SA08]. **Sequence** [Ano07e]. **Sequences** [Hly09c]. **Sequential** [BGD05, COR08, MWJ06, RBM08, RBM11, Sar06, LCdC06, Kat08b, Sar03]. **Serially** [Zho01]. **Series** [Ano03z, Ano03s, Ano05-34, Ano06-33, Ano06j, Ano07s, Bur07, Cab00, Cam01b, Che01c, COR08, Fot07b, Hin05, Hly09b, Lu04a, McC03c, Mye05b, Ray03a, Ruk02, Sca05, She09, Zie01a, Zie04r, Ano04-29, Ano04t, Ano04f, Ano06f, Cha01c, Kar07a, McC05a, Sar02, Zie00c, Zie02-50, Zie02m, Ano07t, Bor02]. **Service** [Oli09d]. **Seshadri** [Bas00]. **Set** [Zha05]. **Setting** [Ke07]. **Settings** [GJS09]. **Setup** [LCdC06]. **Several**

[FS08, WLER06]. **Shaarawi** [Zie02y, Ano05-41]. **Shade** [Law01]. **Shaefer** [San08a]. **Shafer** [Maz00]. **Shaikh** [Neu08c]. **Shaked** [Ano08q]. **Shalabh** [Ano09k]. **Shanbhag** [Ano04j]. **Shane** [Hor09a]. **Shanthikumar** [Ano08q]. **Shao** [Con01, Ano04-28, Boo05a]. **Shape** [Epi08]. **Shapes** [Ano07h, Weh04]. **Sharon** [Zie00-39]. **Shawe** [Bre05a]. **Shawe-Taylor** [Bre05a]. **Shayle** [Von03]. **Shayne** [Zie00-48]. **Shein** [Ano04-28, Ano05-54, Zie00j, Zie01q]. **Shein-Chung** [Ano04-28, Ano05-54, Zie00j, Zie01q]. **Sheldon** [McG07, Sau05]. **Shephard** [Ano06-27]. **Sherali** [Mur07]. **Sheskin** [Ano07i, Nas01, Zie04i]. **Shetty** [Mur07]. **Shewhart** [RS05]. **Shi** [Buk09]. **Shiboski** [Gol06b]. **Shifts** [HZ05]. **Shin** [Alt06]. **Shirley** [Bre05b]. **Shizuhiko** [Bur08a]. **Short** [BH08, BCBS08a, BCBS08b, Gol08, HB08, Jon08, KL08, TH05, ŽH09]. **Short-Range** [ŽH09]. **Short-Run** [TH05]. **shortfall** [DGS07]. **Shoukri** [Zie00-45, Nag04]. **Should** [RS05]. **Shuttle** [FK00]. **Sidani** [Neu09b]. **Sided** [KM04, LLI05, UL07, BG06]. **Siegmund** [Qu08, Ram00a]. **Siem** [Ano06-27]. **Sigma** [Ale01, Ale02, Ano03-36, Ano03-35, Ano04u, Ano06-36, Bai07a, Bzi04, Gar00, Gol04, Kal03, Kal06, Mor04, Mor05b, Rum06, Won04, Zie02-48, Zie02-51, Zie02-47, Zie04k, Zie04o, Zie04p, Ano03q, Ano04m, Ano05p, Sau07, Zie00-51, Zie01x, Zie01m, Zie02-49, Zie04o]. **Sigma**^{TM} [Ano03-48]. **Signal** [Bab05, Cab06, Cha02b, Con05, HPP01, HC00, Liu06, ME05, Sca02, Zie01n]. **Signals** [Ano00e, BJL^{+}07, Hen01, SBD98]. **Significance** [Ahm04]. **Significant** [Lan01]. **Sik** [Cha08b, CL03]. **Sik-Yum** [Cha08b]. **Silverman** [Ano06-41, Alt03]. **Simar** [Hec05]. **similarity** [FVB02]. **Simon** [Aba01b, Ano05-54, Chi07, Cob02, Cob04, Qia02, Gol07]. **Simonoff** [Das04]. **Simple** [Chi01, IM02]. **Simplified** [Ale02, Bre07, Rut00, Sta00, Con00]. **Simplifying** [RF05]. **Simulation** [Ahm08d, Ano07g, Den06, Hes04, Lew04, Ode00a, Pic05, Zie00-30, Ano04j, Zie00v, Bur09a, Qia07]. **Simulations** [LHB^{+}02]. **Simultaneous** [HSR09, JM01, TVW05]. **Sincich** [Zie00-38]. **Singer** [Ano06-39, Ano05-29]. **Singh** [Car07c]. **Singhal** [Ano06n]. **Single** [HCSC07, KJ09, ST02, ZZJ07, vB02]. **Single-Case** [vB02]. **Single-Error-Term** [HCSC07]. **Singpurwalla** [Aba01b, Gho08b]. **Singular** [Ruk01]. **Sinha** [Ye00, Zha05, Zie02s]. **Sir** [Ano07r, Ano07s, Gho07]. **Sirken** [Zie00e]. **Site** [Ste09b]. **Sitter** [Ste07]. **Sivo** [Ano03-34]. **Six** [Ano03-48, Ano03q, Ano04m, Ano05p, Ano06-36, Gar00, Gol04, Kal03, Mor05b, Rum06, Sau07, Won04, Zie00-51, Zie01x, Zie01m, Zie02-48, Zie02-49, Zie02-47, Zie04k, Zie04o, Zie02-51, Ale01, Ale02, Ano03-36, Ano03-35, Ano04u, Bai07a, Bzi04, Kal06, Mor04, Zie02-51, Zie04o, Zie04p]. **Sixten** [Kar07c]. **Size** [CHvdW06, LSW09, MEM05, TTL07, TJ09, Zie04t]. **Sizes** [Ahm06, GV03, Xu09]. **Skew** [Sen05]. **Skew-Elliptical** [Sen05]. **Skiena** [Cha02a]. **Skillicorn** [Cha09]. **Skinner** [Zie04d]. **Skrondal** [Lip05]. **Slaughter** [Hor09c]. **Sliced** [LN06]. **Sloane** [Den00]. **Slutsky** [Ano05p]. **Small** [Ahm07c, BKG09, vB02, CG09, Gan06, HG06, IM05, VD07, WW00, Xu02, Ano04v]. **Small-Area** [Ahm07c]. **Small-n** [vB02]. **Small-Sample** [WW00]. **Smarter** [Gar00]. **Smeeton** [Bar09, Ran03]. **Smeyers** [Zie00u].

Smilde [Boo05b]. **Smirnov** [DGS07]. **Smith** [Ano06-40, Sca02, Fin02, Fri00, Gol06a, Nem02a, Soy04, Ste00b, Zim02]. **Smola** [Ano08n]. **Smooth** [Glu06, Pol01, She09]. **Smoothing** [HCSC07, Qiu04, RSB09, Bak00, Fre03, Zie01-37]. **Smyth** [Owe04]. **Snee** [Ano04m, Zie02-42]. **Soares** [Zie01t]. **Social** [Ano03-45, Ano05-42, Jar09, Mai05]. **Soft** [Mul04, Zie02-40]. **Software** [Aba01b, Aba01a, BE03, Hin06, JLSZ08, Mai01, RLR06, Sar00b, Gun03, Hec09, Zie00b, Zie01-28]. **Software-Based** [Sar00b]. **Solids** [Nem02a]. **Solka** [Ano06s]. **Solomon** [Mic03]. **Solutions** [Gar00]. **Solving** [Per04, Sar05, Zie02-51, Ste00b]. **Some** [CGHL01, Con04, Mal00, RS06, Woo00, KT03]. **Somersalo** [LH06]. **Soofi** [Lu04b]. **Soong** [Yeh05]. **Sophia** [Fri01, Lip05, Zie02n]. **Søren** [O'N03, Zie01h]. **Sorin** [Ano05-53]. **Souraya** [Neu09b]. **Source** [Con05, SA08]. **Sources** [ASW+06]. **Space** [Ano06-27, CL07, FK00, Hin05, JS07]. **Space-Filling** [CL07]. **Space-Shuttle** [FK00]. **Spaces** [SR04]. **Spall** [Hes04]. **Sparks** [Zie01-47]. **Sparse** [CCD09, LN06]. **Spatial** [AL03a, Cob02, Iye02, PC01, Sym01, Sym05, WB05, Woo00, ZCC08, Zie01-42, Nas04, Ros04, Zie04q]. **SPC** [JTW00, Pla02, McC07, Sta00, Yat02]. **Special** [BBS09, Nai07]. **Specification** [Rao01, PDDL02]. **Spectral** [Ano05z, FS08, Zie04r]. **Spectrum** [HTMW08]. **Speed** [Li09, Ano03-49, Cha01a]. **Spencer** [Ano06-42]. **Sperlich** [Ano07v, Lor05]. **Spheres** [JS07]. **Spiegelhalter** [Ano05-56, Ped01]. **Spirer** [Eva01]. **Spirtes** [Bur03]. **Spline** [Bak00, Fre03, RSB09]. **Split** [BS03, But04, GV03, Ke05, KCV02, MB04, PKV07, RACH09, KB05]. **Split-Lot** [But04]. **Split-Plot** [BS03, GV03, Ke05, KCV02, MB04, PKV07, RACH09, KB05]. **Splitstone** [Zie04u]. **Sports** [Ano06-38, Fle09, Zie00-50]. **Sprent** [Bar09, Ran03, Mag00]. **Springer** [Liu07b]. **Sprott** [Mul01, Sca05]. **Spurrier** [Bak01]. **Square** [Sco01]. **Squares** [Bor01, MJH00, Qiu05]. **Sr.** [Che08c]. **SriRaman** [Din05]. **Srivastava** [Kat03b]. **SSA** [Ruk02]. **Stability** [TTL07, TJ09]. **Stacey** [San08a]. **Stage** [Ano08s, BFL02, BMS09, VDLB08]. **Stamatis** [Zie02-51, Ano03-35, Ano04u, Bzi04, Mor04, Zie02-51, Zie04o, Zie04p]. **Standard** [YS05, Zie01-38]. **Standardization** [Ano03-37]. **Stanley** [Ano05-29, Bre05b, Con02a, Lip07a, Zie01c, Zie04y]. **Staroswiecki** [Bar07b]. **Start** [Ano05-28, Ano08j, LC00]. **Started** [SB08]. **Starting** [HMT07, SJ02]. **Stat** [Cha01a]. **STATA** [Das00, Ahm08a, Fri01]. **State** [BGMS03, GS08, Hin05, Ano06-27]. **State-Dependent** [BGMS03]. **STATGRAPHICS** [Zie00-42]. **Statistic** [Ano00e, GS08, KL02, Peñ05, SBD98]. **Statistical** [Ahm04, Ahm07b, Ahm07a, Ahm08a, Ahm08f, AW01, Ano03o, Ano03j, Ano04-30, Ano04e, Ano04q, Ano05-32, Ano05-52, Ano05-27, Ano05j, Ano05-31, Ano05-51, Ano05h, Ano06w, Ano06e, Ano06-35, Ano07r, Ano07s, Ano07e, Ano07i, Ano08l, Ano09m, Ano09f, Bab02b, Bar08b, Bar09, Bat08,

BCL+09, BGMS03, Boo09b, BJL+07, Cab06, Car00, Cha08a, CL03, CW08, DLM+07, Dok08, Edg04, Fri01, Gan02, Gar00, Geo03, Gho01, Han08, HZ05, Hec05, Hec09, Hin06, Hly09a, Jar08, Kaf01c, KML04, Kat03a, Kat08a, Kim00, Kim05, Kuh03, Kuh05b, LaL01, LI08, Law01, Laz03a, LEH03, Lit01, Liu06, Liu09a, Mag00, MM00, Mai05, Maz06b, McC02, McG02, MNS04, MBB05, Mor04, Nas01, Nem04, Old08, Oli07, Per04, Ram00a, Ram00b, Ran03, Rao01, RHOYL06, Rob00b, Rob06, RWZF04, Rum00]. **Statistical** [Rut05, Sar05, Sar00b, Sau02a, Sco01, Sea05, Sin06, Smi02, Spi07, Ste00a, Ste04, Sym01, Taa02, Var00, Weh02, Weh04, Wik03, Wil08a, Wil08b, Wil05, WLLZ07, Yat01, Yat02, Yu07a, ZH06, ZSC06, Zie00m, Zie00f, Zie01v, Zie01e, Zie02i, Zie02j, Zie02-30, Zie02e, Zie03c, Zie04i, Zie04x, MR01, Ano03-49, Ano06-40, Aba01b, AC02, Ann01, Ano03-40, Ano03-39, Ano03-41, Ano03-42, Ano03-43, Ano03-38, Ano04w, Ano04z, Ano04-27, Ano04y, Ano04x, Ano05-46, Ano05-45, Ano06-42, Ano06-43, Ano06-28, Ano06-29, Ano08p, Ano09l, Bai04, Bel01, Cam02, Che01b, Che07, Cob04, Con00, Dav03, Fle09, Fri00, Glo01, Glo06, Gol04, Gol07, Gup00, Hap00, Hof00, HR05, Hus08, Jar09, Joh03, Kaf03, Kar07f, Kat09, Ke06, Ken03, Ket00, Kus03, Laz03b, LH06, McC06a, McC05b]. **Statistical** [Mit02, Mul01, Mye09c, Nem08, Neu01, Neu03, Neu08c, O'N05, Owe00, Pet03a, Pla01, Pry03, Qia05, Qiu02, Rom06, Sen00, Sym05, Utl05, Wlu03, Ye00, Zie00-45, Zie00-44, Zie00-46, Zie00-47, Zie00-42, Zie00-43, Zie01-43, Zie01-41, Zie01-44, Zie01-39, Zie01-42, Zie01-40, Zie02-42, Zie02-41, Zie02g, Zie03b, Zie04u, Zie04s, Zie04t, Zie05a, Zim02]. **Statistically** [Car07c]. **Statistician** [Dok09, Ahm07c]. **Statisticians** [Ano05-49, Zel00]. **Statistics** [Ami04, Ann03, Ano03-35, Ano03p, Ano03-28, Ano03-32, Ano04j, Ano04k, Ano05g, Ano05-39, Ano05u, Ano06-38, Ano06u, Ano06s, Ano06-40, Ano07s, Ano07l, Ano08j, Ano09i, Ano09b, Bak01, Bar08b, Bod02b, Boo09b, Bri04, Bri05, Car07b, CGHL01, Cha01a, Che08c, Cla04a, Con05, Das07b, Dra04, Fah07, FR07, Geo00, Gho07, GLV02, Goo02, Gru08, HI00, HG02, Jen09b, JL07, Ke08, Ker03, Kib07, Kim04, Kus02, LaL04b, Lip06a, Lu08, Lum01, McC03b, Mic01, Mor05b, Mye05a, Nai07, Nas04, Nel00a, Ng05, Ng09, Ode00b, Oli04, Oli09a, Qu08, Rag01, San03a, San08a, Sau02b, Sau05, Sau07, Sho03, SBF+08, Van04, Ye03, Yeh05, Zie00d, Zie00x, Zie00y, Zie00z, Zie00w, Zie00-38, Zie00b, Zie01-27, Zie01-38, Zie01i, Zie01l, Zie01-34, Zie01e, Zie02q, Zie02p, Zie02b, Zie02r]. **Statistics** [Zie04q, Zie04m, Zie04h, Zim01, Ano06-37, Ahm08e, Ano03g, Ano03-47, Ano04l, Ano04h, Ano05t, Ano05-44, Ano05-30, Ano05w, Ano05-28, Ano06-37, Ano07w, Ano07t, Ano08h, Ano08i, Bai05, Boo04b, Bur01a, Cha04, Eva01, Fot04, Fot07a, Gan05, Gro00, Hec01, Hen01, Kar07d, Kat03b, Liu07b, Mai08, Mar06, McG07, Neu09a, Owe03, Owe06, Rut09, Sea02, Sea09, Smi06, Was02, Yeh07, Zie00t, Zie01-50, Zie01q, Zie01g, Zie01w, Zie01-32, Zie02-34, Zie02-27, Zie02-39, Zie04b, Zie04y, Ano03-51, Ano04-28, Ano05-47, Ano05-57, Ano05-48, Ano06-30, Baj00, Bre05b, Bri03, Bur08b, Das00, Hol01, Hor06, Huz03, Jos04, KS07b, LaL09, Laz05, Min02, Neu05, Ng06, Pig06, Rum04, Was04, Zie00-48, Zie00-49, Zie00-50, Zie01-47, Zie01-46, Zie01-48, Zie01-45, Zie02-45, Zie02-44, Zie02-43, Zie04w, Zie04v].

Statistics [Zie05b]. **Stats** [Sch04, Sho05]. **Stauffer** [Gat02]. **Steady** [GS08]. **Steady-State** [GS08]. **Steele** [Ano03-45]. **Steen** [Boo07a]. **Steenstra** [Ano03-37]. **Steepest** [MX08]. **Stefan** [Hly07, Laz03a, Lor05, McC06a]. **Stefano** [Bur09a, Was05]. **Steffen** [Ped01]. **Stein** [Che08c, Che08b, Chi06, Zie00-44, Woo00]. **Steiner** [McC06a]. **Step** [Ano06-37, CE02, Van04]. **Step-by-Step** [Ano06-37, Van04]. **Stepanski** [Ano06-37, Ano06-37]. **Stephan** [Zie00-38, Zie01-45]. **Stephane** [Ano09h]. **Stephanie** [Zie04-27]. **Stephen** [Ano03-34, Ano04-31, Ano07q, Ano08r, Gol06b, Gol07, O'N03, Ray03b, So01, Zie01-38, Zie01d, Zie01h, Zie01-48, Zie02v]. **Stephens** [Ano07l, Hem02]. **Steps** [Sta00, vN02]. **Stereology** [Ano05-49]. **Stern** [Gre04]. **Steve** [Kuh05a, Zie00-33]. **Steven** [Ano03-43, Cha02a, Lum01, Rob06, Sca07, Zie00-47, Zie01-41, Zie01m, Zie02-38, Zie02q]. **Stewart** [Zie06, Ano05x, Qu07a]. **Stigler** [O'N03, Zie01h, Zie01-48]. **Stochastic** [Ahm08d, Ano04j, Ano07s, Bur01b, Bur09a, Cab03, Dob02, FFG06, Fot09, Hes04, Hly09b, HC00, Huz01, Ke09b, Lip06a, McC03a, McC05b, Ode00b, Ros05, Vol05, Ano08q, Fre00, Hor07, Hua00]. **Stoica** [Ano05z]. **Stokes** [Zie01j]. **Stone** [Mai07]. **Stopping** [DM08a]. **Stork** [Bar02]. **Stoyan** [McC03a]. **Strategies** [BN01, Gib01, Hes02, Hof00, MNS04, Wal03]. **Strategy** [Ale01, BFL02, Jia03]. **Stratified** [GHB$^+$07]. **Stream** [Buk09]. **Streams** [GS07]. **Strength** [KMM08, RWZF04, Sha04]. **Stress** [KMM08, Pas06, Sha04]. **Stress-Life** [Pas06]. **Stress-Strength** [KMM08, Sha04]. **strings** [FVB02]. **Strip** [VB09]. **Strip-Block** [VB09]. **Stroup** [Moo03]. **Structural** [Fin05, Lip05, Lip07c, Ano06-31, Cha08b]. **Structure** [Ahm08c, Ruk02]. **Structured** [Ano08n, Ros05]. **Structures** [Mar06]. **Stuart** [Ano06v, Law01, Pig06, Smi02, Sar05]. **Student** [Van04]. **Studies** [Ano03-50, Ano07e, Gun00, HG06, Ye03, Zie00d, Zie00j, Zie04-27, Ano03-34, Ano03-30, Maz06a, Zie01-49]. **Studio** [Ano08o]. **Study** [Ano06o, Bar08a, Che06, Lin02, Mye09c, ZDCS03, Zie00n, BF08, Bri01]. **Stufken** [Den00]. **Stulajter** [McC03c]. **Subhabrata** [Ano04q]. **Subhash** [Weh04]. **Subir** [Bar07c, Zie00-35, Zie00c]. **Subject** [CE02, CR06]. **Subjective** [Ker03]. **Subjectivity** [Gru02]. **Suboptimal** [PW01]. **Subsampling** [Str01]. **Subset** [ÖBMT02, Ano03-44]. **Subsets** [BSC09]. **Sudha** [Ahm07b]. **Sue** [Ano05-37]. **Sujay** [Sar06]. **Sujit** [Zie01s]. **Sulfur** [dCGM05]. **Sullivan** [Ano05-51]. **Sum** [GS08, RS05, Umb01]. **Sumantra** [Sen00]. **Sung** [Zie01-43]. **Supercomputer** [GL09b]. **Supersaturated** [AB03, BFL02, NC08, LD04]. **Supplemental** [Ste09b]. **Support** [BJL$^+$07, Oli08]. **Suren** [Ano06n]. **Surface** [ACBJ09, ALKP02, Ano07o, BV01, FM04, Khu06, Mor00a, MBDD09, TG01, YS05, Zie02-36]. **Surfaces** [Ano07p, GD03, Qiu04, RF05]. **Surrogate** [Ano06-43]. **Survey** [Ahm07c, Ano03r, Ano03k, Ano04s, Ano05-29, Bar08a, Con04, Kar07b, Ke09a, LaL04a, Zie00-35, Zie00e, Zie00h, Zie04d, Ano05-50, Zie02-46]. **Surveys** [Kar07c, Ano05-38, Zie01b]. **Survival** [Ano03-40, Ano04o, Ano05u, Ano07e, Fin02, Gol06b, Ken02, LZ02, Liu04,

Liu07a, ST06, Zie01c, Zie02s, Ano06-32, Ano07u, Rav04]. **Susan** [Ano05n, Hor09c, Zie00e]. **Susanne** [Ano04x, Zie04f]. **Sushmita** [Mul04]. **Svolba** [Nas08]. **Swersey** [Oli09d]. **Sylvan** [Zie02-39]. **Sylvia** [Ros05]. **Sylvie** [Nem08]. **Symmetric** [MBDD09]. **Symmetry** [Smy00]. **System** [BMS09, Glu06, KL02, KD05, VD08, VD07, WKT+03, Zie01-33, Ano08o, Zie00-31, Zie01j, Zie04x]. **Systems** [Che06, Huz00, JW02, LEH03, Mam09, NK03, Ste00a, CFP08, Ano06-33, Ano09h, Ano09l, Fre00, Huz01, Ped01, Ros05, Zie01-41, Zie02-29]. **Székely** [Zie01-46].

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Laz05, Liu09b, Loe07, Lor01, Lu07, McC06c, MS07, Mic05, Mur07, Mye05b, Nel00b, Oli09a, Ord07a, Ord07b, Pas03, Pic06, Qia00, Qia02, Qu07a, Sca04, Sha04, Tor01, Woo00, Zha05, Zie00y, Zie04x, Zim00, Ahm08f, Ano09e, Zie00k]. **Thermosphere** [RMGR09]. **Thermosphere-Ionosphere** [RMGR09]. **Therneau** [LZ02]. **Theus** [KS07a]. **Thinkers** [McC07]. **Thinking** [Ano06i, Ano06-29, Fle09, Cho06, Law01, Zie02-42, Car07c]. **Thode** [Kap03]. **Thomas** [Ahm04, All01, Ano05-34, Ano05l, Ano08n, Den04, Eas07, HL06, Liu07a, Mor05a, Sea01, Ye00, Zie00-51, Zie01-40, Zie01f, Zie04e, Ano08p, Cam02]. **Thompson** [Ano03-27, Kaf03, Zie02-38]. **Thomson** [Jar08]. **Three** [CW02, MBC00, Mor00a, Mor00b, XCW04]. **Three-Level** [CW02, Mor00a, XCW04]. **Throughput** [Zie03a]. **Thumb** [Pry03]. **Thuraisingham** [Zie00i]. **Tiao** [O'N03, Zie01a, Zie01h]. **Tibshirani** [Ano09m, Zie03c, Ahm09]. **TIE** [RMGR09]. **TIE-GCM** [RMGR09]. **Tijms** [Vol05]. **Tim** [Bas02, Boo05a, Pet03a, Zie01-47]. **Time** [Ahm07b, Ano03z, Ano03s, Ano04-29, Ano04t, Ano04f, Ano05-34, Ano06j, Ano06f, Ano07s, BDNN04, Bre06, Bur07, Cab00, Cam01b, Cha01c, Cha02b, Che01c, COR08, FFG06, Fot07b, FW06, Geo03, JS07, Kar07a, Lu04a, McC03c, McC05a, Nas02, RCGD06, Ray03a, RLR06, Ruk02, Sar02, Sca05, She09, Zie00c, Zie01a, Zie02m, Zie04r, McC05b, Ano06-33, Bor02, Fot01, Hin05, Mye05b, Ruk01, Zie02-50]. **Time-Dependent** [RLR06]. **Time-Frequency** [Cha02b, Nas02]. **Time-Series** [Sca05, Zie04r, Bor02]. **Time-to-Event** [Bre06]. **Time-Truncated** [BDNN04]. **Time-Varying** [RCGD06]. **Times** [McC06b, Bri01]. **Timm** [Ahm08g, Boo03]. **Timothy** [Bri03, Zie01-49]. **Tinku** [Mul04]. **Tinsley** [Rob06]. **Titterington** [Zie02t, Zie00-49]. **Tobias** [Nag06, Zie00-34, Hor09b]. **Todd** [Gho01]. **Todinov** [Ke07]. **Todman** [vB02]. **Together** [Bak01]. **Tolerance** [FG01, HJMW04, KM04, KMM08, LLI05, WT09, BF08]. **Tolerant** [Bar07b]. **Tom** [Bre07, Dan01, Zie04a]. **Tomas** [Zie04a]. **Tomasz** [Ano06-43]. **Tomer** [Ano06-31]. **Tomography** [Mai01]. **Tong** [CL03]. **Tony** [Kar07e, Zie04a]. **Toolbox** [McC08]. **Tools** [ACBJ09, Ano04-27, Ano05-53, Bre07, Hof00, MSM03, PYC07, SB04, Zie04u, Ano07x]. **Top** [Ale01]. **Topics** [Ano07o]. **Tormod** [Zie04a]. **Torresani** [Nas02]. **Torsten** [Liu09b, Ord07a, Ord07b]. **Torster** [Ano06e]. **Tourangeau** [Zie00e]. **Toutenburg** [Bor01, Wlu03]. **Townend** [Ano05-39]. **Townsend** [Esp07]. **Toxicologists** [Zie00-48]. **Track** [Ano06-30, Bur08b]. **Tracking** [JL07, Ano09c]. **Tradition** [Hun00]. **Tragic** [Ste07]. **Transform** [Boo05a]. **Transformation** [Atk05]. **Transformations** [Coo00b, CO01, RA00]. **Transforms** [Cha02b, Nas02]. **Transient** [BJL+07]. **Transport** [Li05]. **Transportation** [Cob04]. **Tranter** [Nem02b]. **Treatments** [FHR06]. **Trees** [Ano09c, Jen08]. **Trend** [LEH03]. **Trend-Renewal** [LEH03]. **Trends** [Ano07h]. **Trevor** [Ano03-29, Ano09m, Zie03c]. **Trewn** [Kuh05b]. **Trial** [Hec01]. **Trials** [Ano04-31, Ano05-56, Che07, Chi06, Gol07, Zie04-27, Ano04-31, Zie04-27, Ano03-33, Ano03f, Ano05-54, Hus08, Sin07, Zie02w, Zie04l]. **Triola** [Bai04].

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Variables
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Variance
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